DATASHEET

RZ/V2L Group
RZ 32 & 64-bit MPUs, RZ/V Series

R01DS0485EJ0110
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Features

This LSI has following features.

■ CPU

- Arm® Cortex®-A55, dual-core or single-core [option]

  Max. operating frequency: 1.2 GHz
- Arm® Cortex®-M33, single-core

  Max. operating frequency: 200 MHz

■ Vision and AI

- AI Accelerator; DRP-AI

  Image Signal Processor (Simple ISP) Function is provided as DRP Library

■ On-chip SRAM and external memory interfaces

- On-chip shared SRAM (128-Kbytes on-chip SRAM with ECC)
- External DDR memory interface

  1-channel memory controller for DDR3L-1333 or DDR4-1600 with a 16-bit bus width
- SPI Multi I/O Bus Controller × 1 channel (8-bit Double data rate)
- SD card host interface × 2 channels
- Multimedia card interface × 1 channel (Shared with SDHI)

■ Video and Graphics

- H.264 Video codec processor
- 3D Graphics Engine of Arm® Mali™-G31
- Image Scaling Unit

■ Camera and display interfaces

- Video input interface

  Selectable MIPI CSI-2 × 1 channel or Digital parallel input × 1 channel
- Video display interface

  Selectable MIPI DSI × 1 channel or Digital parallel output × 1 channel

■ Various communication/storage/network interfaces

- USB 2.0 × 2 channels (Host only 1 channel/Host-Function 1 channel)
- Gigabit Ethernet controller × 2 channels
- CANFD interface × 2 channels
- I²C bus interface × 4 channels
- Serial communication interface (SCI) × 2 channels
- Serial communication interface with FIFO (SCIF) × 5 channels
- Serial Peripheral Interface (RSPI) × 3 channels

■ Extended-function timers

- General PWM timer

  32-bit × 8 channels
- Multi-Function Timer Pulse Unit

  32-bit × 1 channel, 16-bit × 8 channels

■ Audio

- Serial sound interface × 4 channels

■ Analog/Digital converter (ADC) and sensor

- 12-bit A/D converter × 8 channels
- Thermal Sensor Unit × 1 channel

■ Security

- Hardware cryptographic engine [option]

1. Overview

1.1 Outline of Specification

1.1.1 CPU Core

Item	Description
System CPU Cortex-A55	[RZ/V2L] • Arm Cortex-A55 Dual / Single MPCore 1.2 GHz • L1 I-cache 32 Kbytes (Parity) / D-cache 32 Kbytes (ECC) • L2 cache 0 Kbyte • L3 cache 256 Kbytes (ECC) • Arm® NEON™ / FPU supported • Cryptographic Extension supported • Arm® v8.2-A architecture
System CPU Cortex-M33	[RZ/V2L] • Arm Cortex-M33 Processor 200 MHz • Security Extension supported • Arm® v8-M architecture
Boot	[RZ/V2L] • 6 boot modes Boot Mode 0: Booting from eSD Boot Mode 1: Booting from eMMC (1.8 V) Boot Mode 2: Booting from eMMC (3.3 V) Boot Mode 3: Booting from a serial flash memory (Single / Quad / Octal) connected to the SPI Multi I/O bus space (1.8 V) Boot Mode 4: Booting from a serial flash memory (Single / Quad) connected to the SPI Multi I/O bus space (3.3 V) Boot Mode 5: Booting from SCIF download
Debug Interface	[RZ/V2L] • Arm® CoreSight™ architecture • JTAG / SWD interface supported • ETF 16 Kbytes for program flow trace (each cluster) • JTAG Disable supported

1.1.2   CPU Peripheral

Item	Description

Clock Pulse Generator (CPG)	[RZ/V2L]
	• Generates the clocks from external clock (EXCLK 24 MHz).
	    Maximum Arm Cortex-A55 clock: 1.2 GHz
	    Maximum Arm Cortex-M33 clock: 200 MHz
	    Maximum DDR clock: 666 MHz (DDR3L-1333), 800 MHz (DDR4-1600)
	    Maximum 3DGE clock: 500 MHz
	    Maximum VCP clock: 200 MHz
	    Maximum AXI-bus clock: 200 MHz
	    Maximum APB-bus clock: 100 MHz
	• SSC (Spread Spectrum Clock) supported

Direct Memory Access Controller (DMAC)	[RZ/V2L] • 2 modules, 16 channels per module • Transfer request: On-chip peripheral request / auto request (software trigger) • A specific DMA transfer interval can be specified to adjust the bus occupancy. • LINK mode (DMA transfer under descriptor control) supported • Transfer information can be automatically reloaded
Interrupt Controller	[RZ/V2L] • Arm® CoreLink™ Generic Interrupt Controller (GIC-600) for Arm Cortex-A55 • Nested Vectored Interrupt Controller (NVIC) for Arm Cortex-M33 • External Interrupt pins (NMI, IRQ7 to IRQ0, TINT31-0) • On-chip peripheral Interrupts: Priority level set for each module
Message Handling Unit (MHU)	[RZ/V2L] • Message handling function between Arm Cortex-A55 and Arm Cortex-M33 • Assert interrupt to inform message and response from/to Arm Cortex-A55, Cortex-M33
General-purpose I/O (GPIO)	[RZ/V2L] • General-purpose I/O ports
Thermal Sensor Unit (TSU)	[RZ/V2L] • 1 channel

1.1.3   Internal Memory

Item	Description
On-chip RAM	[RZ/V2L] • RAM of 128 Kbytes (ECC)

1.1.4 External Memory Interface

Item	Description
External Bus Controller for DDR3L / DDR4 SDRAM (DDR)	[RZ/V2L] • Support DDR3L-1333 / DDR4-1600 • Bus Width: 16-bit • In line ECC supported (Support error detection interrupt) • Memory Size: Up to 4 Gbyes • Auto Refresh supported

SPI Multi I/O Bus Controller	[RZ/V2L]
	 • 1 channel (8-bit Double data rate)
	 • Up to 2 serial flash memories with multiple I/O bus sizes (single / quad) can be connected
	
	    Note: Not Supported for operating as two independent serial flash memories.
	 • Connectable with 1 Octal-SPI flash memory
	 • Connectable with 1 HyperFlash memory
	 • External address space read mode (built-in read cache)
	 • SPI operation mode
	 • Maximum Clock Frequency:
	    – 50 MHz (Quad-SPI DDR)
	    – 66 MHz (Quad-SPI SDR)
	    – 100 MHz (Octal-SPI, HyperFlash)

SD Card Host Interface / Multimedia Card Interface (SD/MMC)	[RZ/V2L] • 2 channels • Channel 0 supports SDHI / e-MMC (boot supported) • Channel 1 supports SDHI • SD memory I/O card interface (1-bit / 4-bit SD bus) • SD, SDHC and SDXC SD memory card access supported • Compliant with SD 3.0 • Default, high-speed, UHS-I/SDR50, SDR104 transfer modes supported • Error check function: CRC7 (Command/response), CRC16 (Data) • Card detection function, write protect supported • MMC interface (1-bit / 4-bit / 8-bit MMC bus) • e-MMC device access supported • Compliant with eMMC 4.51 • High-speed, HS200 transfer modes supported

1.1.5 Graphics Unit

Item	Description
3D Graphics Engine (3DGE)	[RZ/V2L] • Arm Mali-G31 • One single-pixel shader core • 8 Kbytes L2 Cache • OpenGL ES1.1 / 2.0 / 3.0 / 3.1 and 3.2 Supported • OpenCL 2.0 Full Profile Supported

1.1.6 Video Processing Unit

Item	Description
Video Codec Processor (VCP)	[RZ/V2L] • H.264 codec module • Encoding / Decoding support – H.264 / AVC (High Profile / Main Profile / Baseline Profile) – H.264 / MVC (Stereo High Profile) • Maximum pixel rate: 1920 × 1080 × 30 fps • Color format (input in encoding): YcbCr 4:2:0 semi-planar supported • Color format (output in decoding): YcbCr 4:2:0 semi-planar supported
Image Scaling Unit (ISU)	[RZ/V2L] • Scaling down function with bilinear interpolation • Input image Size (max): 5M (2800 × 2047) • Output image Size (max): Full HD (1920 × 1080) • Support Color format Conversion • RGB / ARGB / YcbCr422 / YcbCr420 / RAW (Grayscale)

1.1.7 Camera Interfaces

Item	Description
MIPI CSI-2 Interface	[RZ/V2L] • 1 channel • The number of Lane: 1-/2-/4-lane • Support 5MP, 30 fps (RAW12) • Maximum Bandwidth: 1.5 Gbps per lane • Select 1 VC from 4 VC (virtual channel) supported • Support Input Image Data Formats: – YUV420 8-bit / 10-bit – Legacy YUV420 8-bit – YUV420 8-bit / 10-bit (Chroma Shifted Pixel Sampling) – YUV422 8-bit / 10-bit – RGB444 / RGB555 / RGB565/ RGB666 / RGB888 – RAW6 / RAW7 / RAW8 / RAW10 / RAW12 / RAW14 / RAW16 / RAW20 • Generic short packet code 1 / 2 / 3 / 4 / 5 / 6 / 7 / 8 • Generic long packet data type 1 / 2 / 3 / 4 • User Defined 8-bit data type 1 / 2 / 3 / 4 / 5 / 6 / 7 / 8
Parallel Input Interface	[RZ/V2L] • 1 channel • Support ITU-R BT.656 Interface (Interlace supported, YcbCr422 8-bit / 10-bit) • Support HD – 30 fps (YCbCr422 Interleave), 60 fps (YCbCr422 Y/CbCr separate data, binary data) – Maximum input pixel frequency: 108 MHz • Support Input Data Format: – YcbCr422 8-bit / 10-bit – Binary data 16-bit • VSYNC / HSYNC / FIELD timing signal supported

Item	Description

MIPI CSI-2 / Parallel to AXI Bridge Module	[RZ/V2L]
	• 1 channel (MIPI CSI-2 Input or Parallel Input)
	• Support Image Processing:
	  – Clipping
	  – Frame Sampling
	  – LUT
	  – Color format conversion
	  – Color space conversion
	  – Demosaicing
	  – Linear Matirix
	  – Statistics
	• Support Color Formats for Image Processing:
	  – YUV422 8-/10-bit
	  – RGB565 / RGB666 / RGB888
	  – RAW8 / 10 / 12 / 14 / 16 (Clipping and Frame Sampling only)
	• Support Output Data Formats:
	  – YCbCr422 8-bit (Interleave/Semi planar, Interlace/Progressive)
	  – YCbCr420 8-bit (Interleave, Interlace)
	  – Y-Only
	  – RGB888 / ARGB8888
	  – RAW8 / 10 / 12 / 14 / 16 (without Image Processing)
	  – MIPI CSI-2 V2.1 Recommended Memory storage data (without Image Processing)

1.1.8   Display Interface

Item	Description

LCD Controller	[RZ/V2L]
	• 1 channel (MIPI DSI output or Parallel output)
	• 2 planes blending (can blend 2 different size images)
	• Support Image Processing:
	  – Dither processing (RGB666)
	  – Clipping
	  – RGB Gamma Correction LUT
	• Support Input Data Format:
	  – RGB565 / RGB666 / RGB888
	  – ARGB1555 / ARGB4444 / ARGB8888
	  – YcbCr444 8-bit / YcbCr422 8-bit / YcbCr420 8-bit

MIPI DSI Interface	[RZ/V2L] • 1 channel • The number of Lane: 4-lane • Support up to Full HD (1920 × 1080), 60 fps (RGB888) • Maximum Bandwidth: 1.5 Gbps per lane • Support Output Data Format: – RGB666 / RGB888
Parallel Output Interface	[RZ/V2L] • 1 channel • Support WXGA (1280 × 800), 60 fps • Support Output Data Format: – RGB666 / RGB888 • CLK / HD / VD timing signal supported

1.1.9   Sound Interface

Item	Description
Serial Sound Interface (SSI)	[RZ/V2L] • 4 channels bidirectional serial transfer • 2 external clock sources available • Full Duplex communication (channel 0, 1, and 3) • Support of I2S / Monaural / TDM audio formats • Support of master and slave functions • Generation of programmable word clock and bit clock • Multi-channel formats • Support of 8, 16, 18, 20, 22, 24, and 32-bit data formats • Support of 32-stage FIFO for transmission and reception • Support of LR-clock continue function in which the LR-clock signal is not stopped

1.1.10   Storage and Network

Item	Description
USB2.0 Host / Function (USB)	[RZ/V2L] • 2 channels (ch0: Host-Function ch1: Host only) • Compliance with USB2.0 • Supports On-The-Go (OTG) Function • Supports Battery Charging Function • Internal dedicated DMA
Gigabit Ethernet Interface (GbE)	[RZ/V2L] • 2 channels • Supports transfer at 1000 Mbps and 100 Mbps, 10 Mbps • Supports filtering of Ethernet frames • Supports interface conforming to IEEE802.3 PHY RGMII (Reduced Gigabit Media Independent Interface) • Supports interface conforming to IEEE802.3 PHYMII (Media Independent Interface)
CANFD Interface (RS-CANFD)	[RZ/V2L] • 2 channels • ISO 11898-1 (2003) compliant • CAN-FD ISO 11898-1 (CD2014) compliant • Message buffer – Up to 64 × 2-channel receive message buffer: Shared among all channels – 16 transmit message buffers per channel

1.1.11　Timer

Item	Description
Multi-function Timer Pulse Unit 3 (MTU3a)	[RZ/V2L] • 9 channels (16 bits × 8 channels, 32 bits × 1 channel) • Module clock frequency (P0ϕ): 100 MHz • Maximum 28 lines of pulse inputs/outputs and 3 lines of pulse inputs • 14 types of count clocks selectable • Input capture function • 39 outputs compare and input capture registers • Counter clear operation (Simultaneous counter clearing by Compare match or Input capture is available) • Simultaneous writing to multiple timer counters (TCNT) • Synchronous input/output of each register due to synchronous operation of the counter • Buffered operation • Cascade-connected operation • 43 types of interrupt sources • Automatic transfer of register data • Pulse output modes 　Toggle, PWM, complementary PWM, and reset-synchronized PWM modes • Synchronization of multiple counters • Phase counting mode 　– 16-bit mode (channel 1 and 2) 　– 32-bit mode (channel 1 and 2) • Counter function of dead time compensation • Digital filter functions for the input capture and external count clock pin
Port Output Enable 3 (POE3)	[RZ/V2L] • Control of the high-impedance state of the MTU3a waveform output pins • Activation with four input pins • Activation on detection of short-circuited outputs (detection of simultaneous PWM output to the active level) • Activation by register write • Additional programming of output control target pins is possible.
General PWM Timer (GPT)	[RZ/V2L] • 32 bits × 8 channels • Counting up or down (sawtooth wave), counting up and down (triangular wave) selectable for all channels • Independent selectable for each channel • 2 input/output pins per channel • 2 output compare / input capture registers per channel • For the 2 output compare / input capture registers of each channel, 4 registers are provided as buffer registers and are capable of operating as comparison registers when buffering is not in use • In output compare operation, buffer switching can be at peaks or troughs, enabling the generation of laterally asymmetrically PWM waveforms • Registers for setting up frame intervals on each channel (with capability for generating interrupts on overflow or underflow) • Generation of dead times in PWM operation • Synchronous start / stop / clear of counters on arbitrary channels • Starting, stopping, and clearing up/down counters in response to a maximum of eight events • Starting, stopping, and clearing up/down counters in response to input level comparison • Starting, stopping, and clearing up/down counters in response to a maximum of four external triggers • Output pin invalidation functions due to dead time error or detection of short circuit between output pins • Digital filter functions for the input capture and external trigger pins

Item	Description
Port Output Enable for GPT (POEG)	[RZ/V2L] • Output prohibition control of the GPT waveform output pin • Activation with up to four input pins • Activation by dead time error detection or output short detection • Activation by register write
Watchdog Timer (WDT)	[RZ/V2L] • 3 channels • A counter overflow can reset the LSI • CPU parity error can reset the LSI

General Timer (GTM)	[RZ/V2L]
	• 32 bits × 3 channels
	• Two operating modes
	  – Interval timer mode
	  – Free-running comparison mode

1.1.12   Peripheral Module

Item	Description
I2C Bus Interface (I2C)	[RZ/V2L] • 4 channels • Master mode and slave mode supported • Support for 7-bit and 10-bit slave address formats • Support for multi-master operation • Timeout detection
Serial Communication Interface with FIFO (SCIFA)	[RZ/V2L] • 5 channels • Clock synchronous mode or asynchronous mode selectable • Simultaneous transmission and reception (full-duplex communication) supported • Dedicated baud rate generator • Separate 16-byte FIFO registers for transmission and reception • Modem control function (channel 0, 1, and 2 in asynchronous mode)
Serial Communication Interface (SCIg)	[RZ/V2L] • 2 channels • Clock synchronous mode, asynchronous mode, or smart card interface mode is selectable • Simultaneous transmission and reception (full-duplex communication) supported • Dedicated baud rate generator • LSB first / MSB first selectable • Modem control function • Encoding and decoding of IrDA communications waveforms in accord with version 1.0 of the IrDA standard (on channel 0)
Renesas Serial Peripheral Interface (RSPI)	[RZ/V2L] • 3 channels • SPI operation • Master mode and slave mode supported • Programmable bit length, clock polarity, clock phase can be selected • Consecutive transfers • LSB first / MSB first selectable

1.1.13   Security

Item	Description

Trusted Secure IP (TSIP) [option]	[RZ/V2L]
	• Security algorism
	  – Common key encryption: AES
	  – Non-common key encryption: RSA, ECC
	• Other features
	  – TRNG (true-random number generator)
	  – Hash value generation: SHA-1, SHA-224, SHA-256, GHASH
	  – Support of Unique ID

One Time Programmable memory (OTP)	[RZ/V2L] • A nonvolatile memory that can be written only once • Security setting, authentication setting are possible • Support one time read function (512 bytes)

1.1.14   Analog

Item	Description

A/D Converter (ADC)	[RZ/V2L]
	• 8 channels
	• Resolution: 12-bit
	• Input Range: 0 V ~ 1.8 V
	• Conversion Time: 1 μs
	• Operation Mode: Select mode / scan mode
	• Conversion Mode: Single mode / repeat mode
	• Condition for A/D conversion start
	  – Software trigger
	  – Asynchronous trigger: External trigger supported
	  – Synchronous trigger: MTU and PWM timer

1.1.15   Others

Item	Description
Boundary Scan	[RZ/V2L] • Boundary scan based on IEEE 1149.1 via JTAG interface is supported. Note that some module pins are not available on this boundary scan.

1.1.16   AI Accelerator

Item	Description
AI Accelerator	[RZ/V2L] • DRP-AI

1.1.17   Power Supply Voltage

Item	Description
Power supply voltage	[RZ/V2L] • V_{DD}, $PLLn\_DV_{DD11}$ (n = 23, 5): 1.05 to 1.15 V • DDR_V_{DDQ}: 1.14 to 1.26 V (DDR4) / 1.283 to 1.45 V (DDR3L) • V_{DD18}, ADC_AV_{DD18}, $PLLn\_AV_{DD18}$ (n = 1, 23, 4, 5, 6): 1.62 to 1.98 V • OTP_V_{DD18}, USB_V_{DD18}, CSI_V_{DD18}, DSI_V_{DD18}: 1.65 to 1.95 V • PV_{DD}: 2.97 to 3.63 V • USB_V_{DD33}: 3.00 to 3.60 V • SDn_PV_{DD} (n = 0, 1), SPI_PV_{DD}: 2.97 to 3.63 V / 1.70 to 1.95 V • $PV_{DD182533}$: 2.97 to 3.63 V / 2.25 to 2.75 V / 1.62 to 1.98 V

1.1.18   Temperature Range

Item	Description
Temperature range	[RZ/V2L] • T_a: −40°C to +85°C[1] • T_j: −40°C to +125°C

Note 1.   If wider temp is required than this range, use case has to be investigated.

1.1.19   Quality level

Item	Description
Quality level	[RZ/V2L] • Industrial usage, etc.

1.1.20   Package

Item	Description
Package	[RZ/V2L] • 551-pin LFBGA, 21-mm square, 0.8-mm pitch • 456-pin LFBGA, 15-mm square, 0.5-mm pitch

1.2   Block Diagram

The LSI internal bus of this LSI consists of the ACPU bus, MCPU bus, and system bus. **Figure 1.1** shows the configuration of the buses.

ACPU bus:

A bus connected to Cortex-A55, DDR memory controllers, image processing units, and Storage and Network

MCPU bus:

A bus connected to Cortex-M33 and serial interface units

System bus:

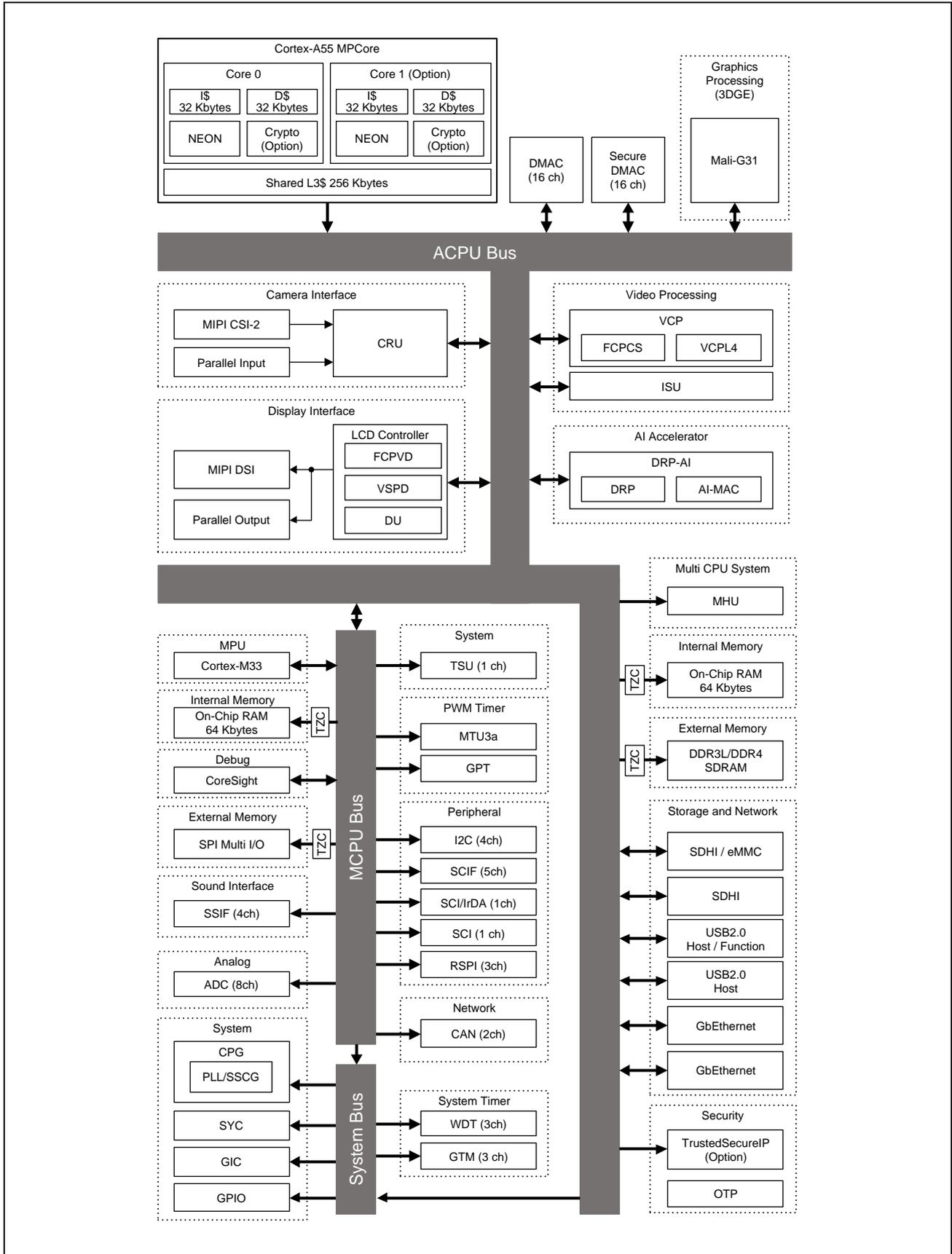A bus connected to the control registers of each unit

Figure 1.1   Configuration of LSI Internal Bus

1.3 Product Lineup

Table 1.1 Product Lineup

Group	Package	Part Number	CPU	Security[1]
RZ/V2L	21 mm BGA	R9A07G054L28GBG	2× Cortex-A55, 1× Cortex-M33	Available
		R9A07G054L18GBG	1× Cortex-A55, 1× Cortex-M33	
		R9A07G054L24GBG	2× Cortex-A55, 1× Cortex-M33	Not supported
		R9A07G054L14GBG	1× Cortex-A55, 1× Cortex-M33	
	15 mm BGA	R9A07G054L27GBG	2× Cortex-A55, 1× Cortex-M33	Available
		R9A07G054L17GBG	1× Cortex-A55, 1× Cortex-M33	
		R9A07G054L23GBG	2× Cortex-A55, 1× Cortex-M33	Not supported
		R9A07G054L13GBG	1× Cortex-A55, 1× Cortex-M33	

Note 1. The product with security function supports the following features.
— Crypto Extension (Cortex-A55 configuration)
— Trusted Secure IP
— Trust Zone[2]
— Secure Software PKG
— Secure Boot
— Secure Debug
— HW Key protection
— True Random Generator
— Trusted Execution Environment (TEE)[2]

Note 2. The product without security function also supports them.

2.   Pin

2.1   Pin Assignment

Refer to attached excel file for the "ball view" about pin assignment of this LSI.

(Please double-click the icon on the right side)

2.2   External Pins and Multiplexed Functional Pins

Refer to attached excel file for the "pn function list" about information of external pins and multiplexed functional pins of this LSI.

(Please double-click the icon on the right side)

3.   Electrical Characteristics

3.1   Absolute Maximum Ratings

Table 3.1   Absolute Maximum Ratings

Item		Symbol	Value	Unit
Power supply voltage (3.3 V)		PV_{DD}	−0.5 to +3.8	V
		USB_V_{DD33}		
Power supply voltage (1.8-V/3.3-V switchable)		$SD0\_PV_{DD}$	−0.5 to +3.8	V
		$SD1\_PV_{DD}$		
		SPI_PV_{DD}		
Power supply voltage (1.8-V/ 2.5-V/ 3.3-V switchable)		$PV_{DD182533\_0/1}$	−0.5 to +3.8	V
Power supply voltage (1.8 V)		V_{DD18}	−0.5 to +2.5	V
		$PLL1\_AV_{DD18}$		
		$PLL23\_AV_{DD18}$		
		$PLL4\_AV_{DD18}$		
		$PLL5\_AV_{DD18}$		
		$PLL6\_AV_{DD18}$		
		CSI_V_{DD18}		
		DSI_V_{DD18}		
		USB_V_{DD18}		
		ADC_AV_{DD18}		
		OTP_V_{DD18}		
DDR power supply voltage (DDR4/ DDR3L switchable)		DDR_V_{DDQ}	−0.5 to +2.5	V
Power supply voltage (1.1-V)		V_{DD}	−0.5 to +1.5	V
		$PLL23\_DV_{DD11}$		
		$PLL5\_DV_{DD11}$		
Input voltage	3.3-V I/O input pins	—	−0.3 to 3.3-V power supply (PV_{DD}, USB_V_{DD33}) + 0.3	V
	1.8-V/3.3-V switchable I/O input pins	—	−0.3 to 1.8-V/3.3-V switchable power supply ($SD0\_PV_{DD}$, $SD1\_PV_{DD}$, SPI_PV_{DD}) + 0.3	V
	1.8-V/2.5-V/3.3-V switchable I/O input pins	—	−0.3 to 1.8-V/2.5-V/3.3-V switchable power supply ($PV_{DD182533\_0.1}$) + 0.3	V
	1.8-V I/O input pins	—	−0.3 to 1.8-V power supply (V_{DD18}, CSI_V_{DD18}, USB_V_{DD18}) + 0.3	V
Operating temperature	Ambient temperature	T_a	−40°C to +85°C[1]	°C
	Junction temperature	T_j	−40°C to +125°C	°C
Storage temperature	Ambient temperature	T_{stg}	−40°C to +150°C	°C

Note 1.   If wider temp is required than this range, use case has to be investigated.

3.2   Power Supply

Table 3.2   Power Supply

Item	Symbol	Min.	Typ.	Max.	Unit	Remarks
Power supply voltage (3.3 V)	PV_{DD}	2.97	3.30	3.63	V	—
Power supply voltage (1.8 V)	V_{DD18}, ADC_AV_{DD18}	1.62	1.80	1.98	V	—
	OTP_V_{DD18}	1.65	1.80	1.95	V	—
Power supply voltage (1.1 V)	V_{DD}	1.05	1.10	1.15	V	—
Power supply voltage (USB)	USB_V_{DD33}	3.00	3.30	3.60	V	—
	USB_V_{DD18}	1.65	1.80	1.95	V	—
Power supply voltage (SD)	$SD0\_PV_{DD}$, $SD1\_PV_{DD}$	2.97	3.30	3.63	V	When 3.3 V is supplied
		1.70	1.80	1.95	V	When 1.8 V is supplied
Power supply voltage (SPI)	SPI_PV_{DD}	2.97	3.30	3.63	V	When 3.3 V is supplied
		1.70	1.80	1.95	V	When 1.8 V is supplied
Power supply voltage (Ether)	$PV_{DD182533\_0/1}$	2.97	3.30	3.63	V	When 3.3 V is supplied
		2.25	2.50	2.75	V	When 2.5 V is supplied
		1.62	1.80	1.98	V	When 1.8 V is supplied
Power supply voltage (CSI)	CSI_V_{DD18}	1.65	1.80	1.95	V	—
Power supply voltage (DSI)	DSI_V_{DD18}	1.65	1.80	1.95	V	—
Power supply voltage (DDR)	DDR_V_{DDQ}	1.14	1.20	1.26	V	When using DDR4
		1.283	1.35	1.45	V	When using DDR3L
Power supply voltage (PLL)	$PLL1\_AV_{DD18}$, $PLL23\_AV_{DD18}$, $PLL4\_AV_{DD18}$, $PLL5\_AV_{DD18}$, $PLL6\_AV_{DD18}$	1.62	1.80	1.98	V	—
	$PLL23\_DV_{DD11}$, $PLL5\_DV_{DD11}$	1.05	1.10	1.15	V	—

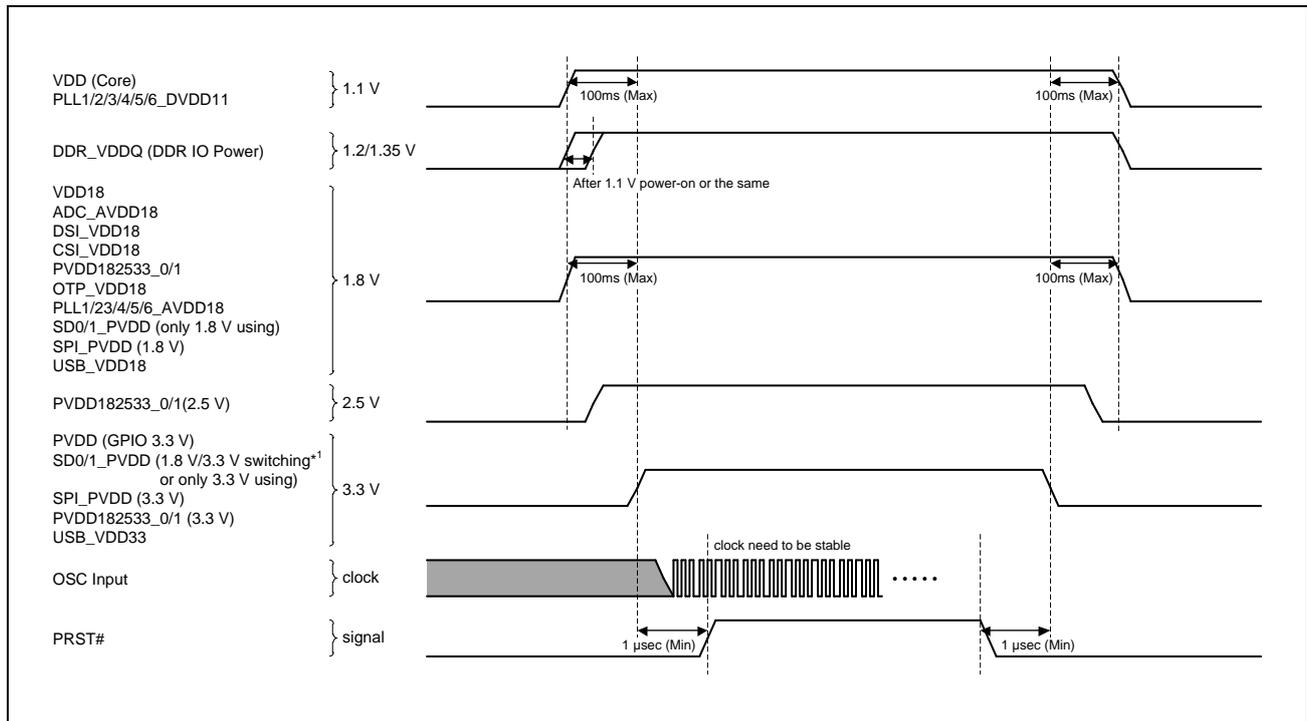## 3.3　Power-On/Power-Off Sequence

Figure 3.1　　Power-On/Power-Off Sequence

NOTES

1.　Turn on 3.3 V after 1.1 V/1.8 V.

　　Note 1.　About SD0/1_PV_{DD}, especially in the case of switching between 1.8 V and 3.3 V at same power rail, 1.8-V power-on/off timing can also follow 3.3-V power rail sequence as shown in the **Figure 3.1**.

2.　Turn on the DDR IO power supply at the same time as or after the 1.1-V power supply.

3.　From first power rising start to last power rising end must be within 100 ms.

4.　The power-off sequence is the reverse of the power-on sequence
　　(PRST# → Low ⇨ 3.3 V = OFF ⇨ Other = OFF)

5.　PRST# should be changed from Low to High after the 3.3-V power supply is turned on, after 1 μsec, and after the input clock from the oscillator stabilizes.

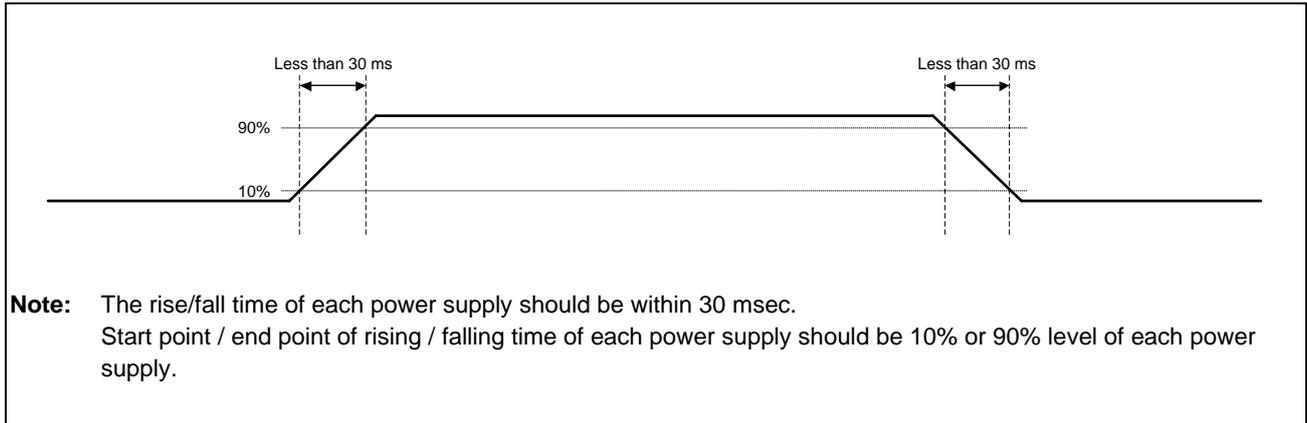6.　Refer to SD0/1_PV_{DD} when connecting eMMC.

Note: The rise/fall time of each power supply should be within 30 msec.
Start point / end point of rising / falling time of each power supply should be 10% or 90% level of each power
supply.

Figure 3.2   Power Up Time/Power Down Time (1)

Note: In case of there is restriction of sequence between different power supply, measurement time is starting point
that is 10% of earlier rising power voltage level to end point that is 90% of later rising power voltage level, and
starting point that is 90% of earlier falling power voltage level to end point that is 10% of later falling power
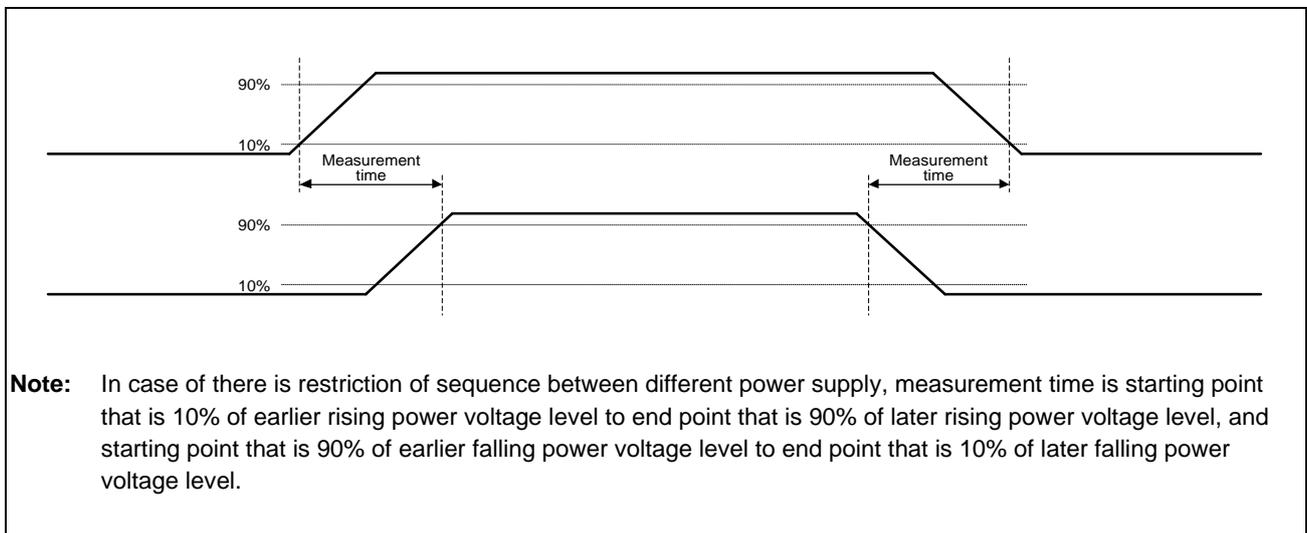voltage level.

Figure 3.3   Power Up Time/Power Down Time (2)

3.4   DC Characteristics

Table 3.3   DC Characteristics (1) [3.3-V I/O]

Item		Symbol	Min.	Typ.	Max.	Unit	Remarks
High-level input voltage		V_{IH}	2	—	PV_{DD} + 0.3	V	
Low-level input voltage		V_{IL}	−0.3	—	0.8	V	
Hysteresis threshold ↑		V_T+	0.9	—	2.1	V	
Hysteresis threshold ↓		V_T-	0.7	—	1.9	V	
Input hysteresis voltage		V_{HYS}	0.306	—	0.420	V	
Output logic high voltage	(I_{OH} = −2mA)	V_{OH}	PV_{DD} − 0.4	—	PV_{DD}	V	
	(I_{OH} = −4mA)						
	(I_{OH} = −8mA)						
	(I_{OH} = −12mA)						
Output logic low voltage	(I_{OL} = 2mA)	V_{OL}	0	—	0.4	V	
	(I_{OL} = 4mA)						
	(I_{OL} = 8mA)						
	(I_{OL} = 12mA)						
Weak pull-up resistor (input mode)		R_{UP}	7K	—	100K	Ω	
Weak pull-down resistor (input mode)		R_{DN}	7K	—	100K	Ω	
Input leakage current		I_{LI}	—	—	5	µA	$0V \le V_{in} \le PV_{DD}$ In case of 3state buffer, the leak current when output mode OFF

Note: V_{in} means input voltage of external input pin.

Note: Schmitt can be used at only RIIC mode.

Table 3.4   DC Characteristics (2) [1.8-V I/O]

Item		Symbol	Min.	Typ.	Max.	Unit	Remarks
High-level input voltage		V_{IH}	$0.65 \times V_{DD18}$	—	V_{DD18} + 0.3	V	
Low-level input voltage		V_{IL}	−0.3	—	$0.35 \times V_{DD18}$	V	
Output logic high voltage	(I_{OH} = −2mA)	V_{OH}	V_{DD18} − 0.4	—	V_{DD18}	V	
	(I_{OH}= −4mA)						
	(I_{OH} = −8mA)						
	(I_{OH} = −12mA)						
Output logic low voltage	(I_{OL} = 2mA)	V_{OL}	0	—	0.4	V	
	(I_{OL} = 4mA)						
	(I_{OL} = 8mA)						
	(I_{OL} = 12mA)						

Table 3.5   DC Characteristics (3) [3.3-V Input]

Item	Symbol	Min.	Typ.	Max.	Unit	Remarks
High-level input voltage	V_{IH}	2.3	—	PV_{DD} + 0.3	V	
Low-level input voltage	V_{IL}	−0.3	—	0.8	V	
Hysteresis threshold ↑	V_T+	0.9	—	2.1	V	
Hysteresis threshold ↓	V_T-	0.7	—	1.9	V	
Input hysteresis voltage	V_{HYS}	0.306	—	0.420	V	

Table 3.6   DC Characteristics (4) [1.8-V Input]

Item	Symbol	Min.	Typ.	Max.	Unit	Remarks
High-level input voltage	V_{IH}	$0.65 \times V_{DD18}$	—	$V_{DD18} + 0.3$	V	
Low-level input voltage	V_{IL}	-0.3	—	$0.35 \times V_{DD18}$	V	

Table 3.7   DC Characteristics (5) [RGMII/MII]

Item	Symbol	Min.	Typ.	Max.	Unit	Remarks
Power supply voltage	$PV_{DD182533\_n}$	2.97	3.3	3.63	V	3.3-V RGMII/MII
Input logic high	V_{IH}	2.6	—	—	V	
Input logic low	V_{IL}	—	—	0.7	V	
Output logic high voltage @ 7.7 mA	V_{OH}	2.1	—	3.6	V	
Output logic low voltage @ 9.3 mA	V_{OL}	0	—	0.5	V	
Power supply voltage	$PV_{DD182533\_n}$	2.25	2.5	2.75	V	2.5-V RGMII/MII
Input logic high	V_{IH}	1.9	—	—	V	
Input logic low	V_{IL}	—	—	0.7	V	
Output logic high voltage	V_{OH}	2.0	—	$PV_{DD182533\_n}$	V	
Output logic low voltage	V_{OL}	V_{SS}	—	0.4	V	
Power supply voltage	$PV_{DD182533\_n}$	1.62	1.8	1.98	V	1.8-V RGMII/MII
Input logic high	V_{IH}	$0.7 \times PV_{DD182533\_n}$	—	$PV_{DD182533\_n} + 0.3$	V	
Input logic low	V_{IL}	$V_{SS} - 0.3$	—	$0.3 \times PV_{DD182533\_n}$	V	
Output logic high @ I_{OH} = 100 µA	V_{OH}	$0.85 \times PV_{DD182533\_n}$	—	$PV_{DD182533\_n}$	V	
Output logic low @ I_{OL} = 100 µA	V_{OL}	V_{SS}	—	$0.15 \times PV_{DD182533\_n}$	V	

Note: n = 0, 1

Table 3.8   DC Characteristics (6) [3.3 V I/O (SD, QSPI)]

Item		Symbol	Min.	Typ.	Max.	Unit	Remarks
High-level input voltage		V_{IH}	$0.625 \times SDn\_PV_{DD}$	—	$SDn\_PV_{DD} + 0.3$	V	
Low-level input voltage		V_{IL}	$SDn\_PV_{DD} - 0.3$	—	$0.25 \times SDn\_PV_{DD}$	V	
Output logic high voltage	(× 0.5)	V_{OH}	$0.75 \times SDn\_PV_{DD}$	—	SDn_PV_{DD}	V	
	(× 0.75)						
	(× 1.0)						
	(× 1.5)						
Output logic low voltage	(× 0.5)	V_{OL}	0	—	$0.125 \times SDn\_PV_{DD}$	V	
	(× 0.75)						
	(× 1.0)						
	(× 1.5)						

Table 3.9   DC Characteristics (7) [1.8 V I/O (SD, QSPI)]

Item		Symbol	Min.	Typ.	Max.	Unit	Remarks
High-level input voltage		V_{IH}	1.27	—	2.00	V	
Low-level input voltage		V_{IL}	$SDn\_PV_{DD} - 0.3$	—	0.58	V	
Output logic high voltage	(× 0.5)	V_{OH}	$0.8 \times SDn\_PV_{DD}$	—	SDn_PV_{DD}	V	
	(× 0.75)						
	(× 1.0)						
	(× 1.5)						
Output logic low voltage	(× 0.5)	V_{OL}	0	—	$0.2 \times SDn\_PV_{DD}$	V	
	(× 0.75)						
	(× 1.0)						
	(× 1.5)						

Table 3.10   DC Characteristics(8) [I²C Open Drain 3.3 V I/O]

Item	Symbol	Min.	Typ.	Max.	Unit	Remarks
External pull-up supply	V_{VDDP}	2.7	—	PV_{DD}	V	
Input high voltage	V_{IH}	$0.7 \times V_{VDDP}$	—	$V_{VDDP} + 0.5$	V	
Input Low Voltage	V_{IL}	−0.5	—	$0.3 \times V_{VDDP}$	V	
Low level output current	I_{OL}	20	—	—	mA	$V_{OL} = 0.4$ V
Low level output voltage	V_{OL}	—	—	0.4	V	$V_{VDDP} > 2$ V
Input hysteresis	V_{HYST}	$0.1 \times V_{VDDP}$	—	—	mV	

Table 3.11   DC Characteristics (9) [1.2-V Input (DDR4)]

Item	Symbol	Min.	Typ.	Max.	Unit	Remarks
DC input high level	$V_{IH}(DC)$	$V_{REF} + 0.068$	—	—	V	
DC input low level	$V_{IL}(DC)$	—	—	$V_{REF} - 0.068$	V	
AC input high level	$V_{IH}(AC)$	$V_{REF} + 0.093$	—	—	V	
AC input Low level	$V_{IL}(AC)$	—	—	$V_{REF} - 0.093$	V	
DC differential input high	V_{IHdiff}	0.136	—	—	V	
DC differential input low	V_{ILdiff}	—	—	−0.136	V	
AC differential input high	$V_{IHdiff}(AC)$	$2 \times (V_{IH}(AC) - V_{REF})$	—	—	V	
AC differential input low	$V_{ILdiff}(AC)$	—	—	$2 \times (V_{REF} - V_{IL}(AC))$	V	
Differential input cross point voltage relative to $0.8 \times V_{DDIO}$ for DQS	$V_{IX}(DQS)$	−0.15	—	0.06	V	

Table 3.12 DC Characteristics (10) [1.35-V Input (DDR3L)]

Item	Symbol	Min.	Typ.	Max.	Unit	Remarks
DC input high level	$V_{IH}(DC)$	V_{REF} + 0.09	—	—	V	
DC input low level	$V_{IL}(DC)$	—	—	V_{REF} − 0.09	V	V_{REF} =0.5 x DDR_V_{DDQ}
AC input high level	$V_{IH}(AC)$	V_{REF} + 0.135	—	—	V	
AC input low level	$V_{IL}(AC)$	—	—	V_{REF} − 0.135	V	V_{REF} =0.5 x DDR_V_{DDQ}
DC differential input high	V_{IHdiff}	0.18	—	—	V	
DC differential input low	V_{ILdiff}	—	—	−0.18	V	
AC differential input high	$V_{IHdiff}(AC)$	2 × ($V_{IH}(AC)$ − V_{REF})	—	—	V	
AC differential input low	$V_{ILdiff}(AC)$	—	—	2 × (V_{REF} − $V_{IL}(AC)$)	V	V_{REF} =0.5 x DDR_V_{DDQ}
Differential input cross point voltage relative to 0.5 × DDR_VDDQ for DQS	$V_{IX}(DQS)$	−0.075	—	0.075	V	

Table 3.13 DC Characteristics (11) [1.2-V Output (DDR4)]

Item	Symbol	Min.	Typ.	Max.	Unit	Remarks
DC output high measurement level (for IV curve linearity)	$V_{OH}(DC)$	—	1.1 × DDR_V_{DDQ}	—	V	The swing of ± 0.15 × DDR_V_{DDQ} is based on approximately 50% of the static single-ended output peak-to-peak swing with a driver impedance of 40Ω and an effective test load of 50Ω to V_{TT} = DDR_V_{DDQ}.
DC output mid measurement level (for IV curve linearity)	$V_{OM}(DC)$	—	0.8 × DDR_V_{DDQ}	—	V	
DC output low measurement level (for IV curve linearity)	$V_{OL}(DC)$	—	0.5 × DDR_V_{DDQ}	—	V	
AC output high measurement level (for output slew rate)	$V_{OH}(AC)$	—	0.85 × DDR_V_{DDQ}	—	V	
AC output low measurement level (for output slew rate)	$V_{OL}(AC)$	—	0.55 × DDR_V_{DDQ}	—	V	

Table 3.14 DC Characteristics (12) [1.35-V Output (DDR3L)]

Item	Symbol	Min.	Typ.	Max.	Unit	Remarks
DC output high measurement level (for IV curve linearity)	$V_{OH}(DC)$	—	0.8 × DDR_V_{DDQ}	—	V	The swing of ± 0.1 × DDR_V_{DDQ} is based on approximately 50% of the static single-ended output high or low swing with a driver impedance of 40Ω and an effective test load of 25Ω to V_{TT} = DDR_V_{DDQ}/2.
DC output mid measurement level (for IV curve linearity)	$V_{OM}(DC)$	—	0.5 × DDR_V_{DDQ}	—	V	
DC output low measurement level (for IV curve linearity)	$V_{OL}(DC)$	—	0.2 × DDR_V_{DDQ}	—	V	
AC output high measurement level (for output slew rate)	$V_{OH}(AC)$	—	VTT + 0.1 × DDR_V_{DDQ}	—	V	
AC output low measurement level (for output slew rate)	$V_{OL}(AC)$	—	VTT − 0.1 × DDR_V_{DDQ}	—	V	

Table 3.15 DC Characteristics (13) [DDR4 Cross Point Voltage for Differential Output Signals (CK/DQS)]

Item	Symbol	Min.	Typ.	Max.	Unit	Remarks
Differential output cross point voltage relative to 0.67 × DDR_VDDQ	$V_{OX}(CK/DQS)$	−0.06	—	0.06	V	

Table 3.16   DC Characteristics (14) [DDR3L Cross Point Voltage For Differential Output Signals (CK/DQS)]

Item	Symbol	Min.	Typ.	Max.	Unit	Remarks
Differential output cross point voltage relative to 0.5 × DDR_VDDQ	V_{OX}(CK/DQS)	−0.1	—	0.1	V	

Table 3.17   DC Characteristics (15) [USB 2.0]

Item	Symbol	Min.	Typ.	Max.	Unit	Remarks
Input levels for low/full speed						
High (driven)	V_{IH}	2.0	—	—	V	
Low	V_{IL}	—	—	0.8	V	
Differential input sensitivity	V_{DI}	0.2	—	—	V	
Differential common mode range	V_{CM}	0.8	—	2.5	V	
Input levels for high speed						
High-speed squelch detection threshold (differential signal amplitude)	V_{HSSQ}	100	—	150	mV	
High-speed data signaling common mode voltage range (guideline for receiver)	V_{HSCM}	−50	—	500	mV	
Output levels for low/full speed						
Low	V_{OL}	0.0	—	0.3	V	
High (driven)	V_{OH}	2.8	—	3.6	V	
Output signal crossover voltage	V_{CRS}	1.3	—	2.0	V	
Output levels for high-speed						
High-speed idle level	V_{HSOI}	−10.0	—	10.0	mV	
High-speed data signaling high	V_{HSOH}	360	—	440	mV	
High-speed data signaling low	V_{HSOL}	−10.0	—	10.0	mV	
Chirp J level (differential voltage)	V_{CHIRPJ}	700	—	1100	mV	
Chirp K level (differential voltage)	V_{CHIRPK}	−900	—	−500	mV	

Table 3.18   DC Characteristics (16) [ADC]

Item	Symbol	Min.	Typ.	Max.	Unit	Remarks
Resolution	—	—	12	—	Bit	
Analog input channel	—	—	—	8	Channel	
Analog input range	AIN	V_{SS}	—	ADC_AV$_{DD18}$	V	
Differential non-linearity	DNL	—	—	±3.0	LSB	
Integral non-linearity	INL	—	—	±6.0	LSB	
Full-scale error	—	—	±10	±20	LSB	
Offset error	—	—	±10	±20	LSB	
Analog input capacitance	C_{IN}	—	—	12.6	pF	
Analog input resistance	R_{IN}	—	—	1785	Ω	
External capacitance	C_{EXT}	—	—	(*1)	pf	
External resistance	R_{EXT}	—	—	(*1)	Ω	

Note 1.   Refer to **Figure 3.4** for Cext and Rext.
           The Cext and Rext need to satisfy the sampling time.
           A/D conversion time = sampling time (6T to 2800T) + 14T.
           T stands for the cycle of ADIVCLK (20 MHz).
           If A/D conversion is performed with the minimum conversion time, the sampling time must be 6T.
           (Minimum conversion time per channel is 1 μs when A/D conversion clock ADIVCLK is 20 MHz.)
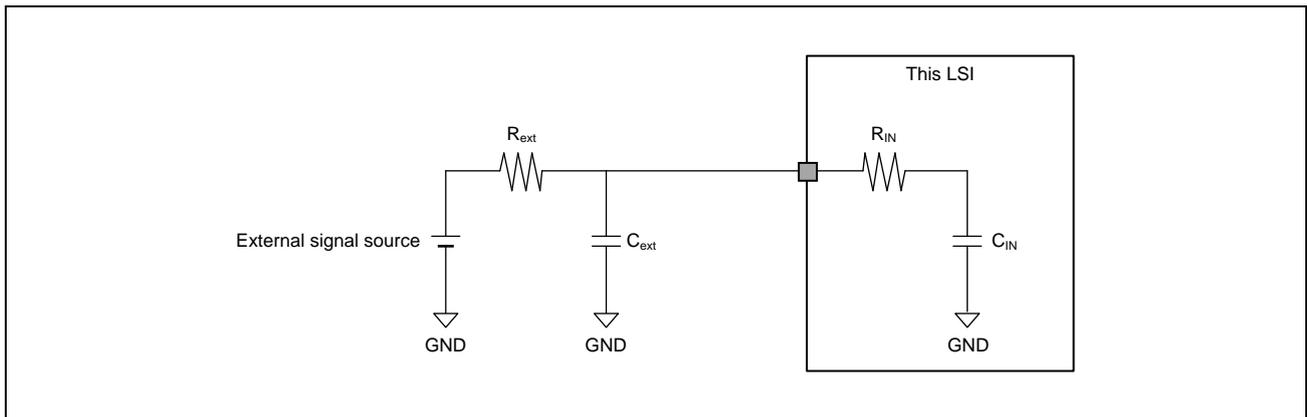
Figure 3.4   Analog Input Equivalent Circuit

Table 3.19   DC Characteristics (17) [Current Consumption]

Item	Power rail symbol	Max Current	Unit	Remarks
Power Supply voltage(3.3V)	PV_{DD}	620	mA	PV_{DD}=3.6V
Power Supply voltage(1.8V)	V_{DD18}	30	mA	V_{DD18}=1.98V
	OTP_AV_{DD18}	20	mA	OTP_V_{DD18}=1.95V
	ADC_AV_{DD18}	10	mA	ADC_AV_{DD18}=1.98V
Power Supply voltage(1.1V)	V_{DD}	4970	mA	V_{DD}=1.15V
Power supply voltage (USB/3.3V)	USB_V_{DD33}	20	mA	USB_V_{DD33}=3.6V
Power supply voltage (USB/1.8V)	USB_V_{DD18}	140	mA	USB_V_{DD18}=1.95V
Power supply voltage (SD/3.3V)	$SD0\_PV_{DD}$	260	mA	$SD0\_PV_{DD}$=3.63V
	$SD1\_PV_{DD}$	170	mA	$SD1\_PV_{DD}$=3.63V
Power supply voltage (SD/1.8V)	$SD0\_PV_{DD}$	110	mA	$SD0\_PV_{DD}$=1.95V
	$SD1\_PV_{DD}$	70	mA	$SD1\_PV_{DD}$=1.95V
Power supply voltage (SPI/3.3V)	SPI_PV_{DD}	100	mA	SPI_PV_{DD}=3.63V
Power supply voltage (SPI/1.8V)	SPI_PV_{DD}	100	mA	SPI_PV_{DD}=1.95V
Power supply voltage (Ether/3.3V)	$PV_{DD182533\_n}$	380	mA	$PV_{DD182533\_n}$=3.63V when 2 channels are in use
Power supply voltage (Ether/2.5V)	$PV_{DD182533\_n}$	240	mA	$PV_{DD182533\_n}$=2.75V when 2 channels are in use
Power supply voltage (Ether/1.8V)	$PV_{DD182533\_n}$	140	mA	$PV_{DD182533\_n}$=1.98V when 2 channels are in use
Power supply voltage (CSI/1.8V)	CSI_V_{DD18}	100	mA	CSI_V_{DD18}=1.95V
Power supply voltage (DSI/1.8V)	DSI_V_{DD18}	100	mA	DSI_V_{DD18}=1.95V
Power supply voltage (DDR/1.2V)	DDR_V_{DDQ}	220	mA	DDR_V_{DDQ}=1.26V
Power supply voltage (DDR/1.35V)	DDR_V_{DDQ}	210	mA	DDR_V_{DDQ}=1.45V
Power supply voltage (PLL/1.8V)	$PLL1\_AV_{DD18}$	10	mA	$PLL1\_AV_{DD18}$=1.98V
	$PLL23\_AV_{DD18}$	20	mA	$PLL23\_AV_{DD18}$=1.98V
	$PLL4\_AV_{DD18}$	10	mA	$PLL4\_AV_{DD18}$=1.98V
	$PLL5\_AV_{DD18}$	10	mA	$PLL5\_AV_{DD18}$=1.98V
	$PLL6\_AV_{DD18}$	10	mA	$PLL6\_AV_{DD18}$=1.98V
Power supply voltage (PLL/1.1V)	$PLL23\_DV_{DD11}$	20	mA	$PLL23\_DV_{DD11}$=1.15V
	$PLL5\_DV_{DD11}$	10	mA	$PLL5\_DV_{DD11}$=1.15V

Note: T_j = 125°C, n = 0, 1

3.5   AC Characteristics

Conditions: V_{DD} = PLL23_DV$_{DD11}$ = PLL5_DV$_{DD11}$ = 1.1 ± 0.05 V,

PLL1_AV$_{DD18}$ = PLL23_AV$_{DD18}$ = PLL4_AV$_{DD18}$ = PLL6_AV$_{DD18}$ = 1.8 ± 0.18 V,

ADC_AV$_{DD18}$ = V$_{DD18}$ = 1.8 ± 0.18 V, OTP_V$_{DD18}$ = 1.8 V ± 0.15 V,

USB_V$_{DD18}$ = CSI_V$_{DD18}$ = DSI_V$_{DD18}$ = 1.8 ± 0.15 V,

PV$_{DD}$ = 3.3 ± 0.33 V, USB_V$_{DD33}$ = 3.3 ± 0.3 V, DDR_V$_{DDQ}$ = 1.2 ± 0.06 V/1.283 to 1.45 V,

SPI_PV$_{DD}$ = SDn_PV$_{DD}$ (n = 0, 1) = 3.3 ± 0.33 V/1.70 to 1.95 V,

PV$_{DD182533\_n}$ (n = 0, 1) = 3.3 ± 0.33 V/2.5 ± 0.25 V/1.8 ± 0.18 V, V$_{SS}$ = 0 V,

T_a = −40 to +85°C, T_j = −40 to +125°C

3.5.1   Clock Timing

Table 3.20   Clock Timing Table

Item	Symbol	Min.	Max.	Unit	Figures
EXCLK clock input frequency	f_{EX}	24 − 50ppm[1]	24 + 50ppm[1]	MHz	**Figure 3.5**
EXCLK clock input cycle time	t_{EXcyc}	41.67	41.67	ns	
AUDIO_CLK1, AUDIO_CLK2 clock input frequency (external clock is input)	f_{EX}	10	50	MHz	
AUDIO_CLK1, AUDIO_CLK2 clock input cycle time (external clock is input)	t_{EXcyc}	20	100	ns	
EXCLK, AUDIO_CLK1, AUDIO_CLK2 clock input low level pulse width	t_{EXL}	0.4	0.6	t_{EXcyc}	
EXCLK, AUDIO_CLK1, AUDIO_CLK2 clock input high level pulse width	t_{EXH}	0.4	0.6	t_{EXcyc}	
EXCLK, AUDIO_CLK1, AUDIO_CLK2 clock input rise time	t_{EXr}	—	4	ns	
EXCLK, AUDIO_CLK1, AUDIO_CLK2 clock input fall time	t_{EXf}	—	4	ns	
Oscillator stabilization time	t_{OSC}	—	1	ms	**Figure 3.6**, **Figure 3.7**
Mode hold time	t_{MDH}	—	100	ns	
Mode setup time	t_{MDS}	—	100	ns	

Note 1.   When using RGMII interface. If not using RGMII mode, this spec is ±100 ppm.
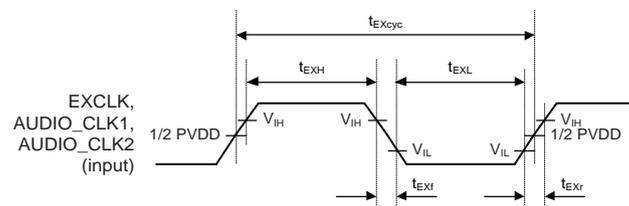
Note: When the clock is input on the EXCLK, AUDIO_CLK1 or AUDIO_CLK2

Figure 3.5   EXCLK, AUDIO_CLK1 and AUDIO_CLK2 Clock Input Timing
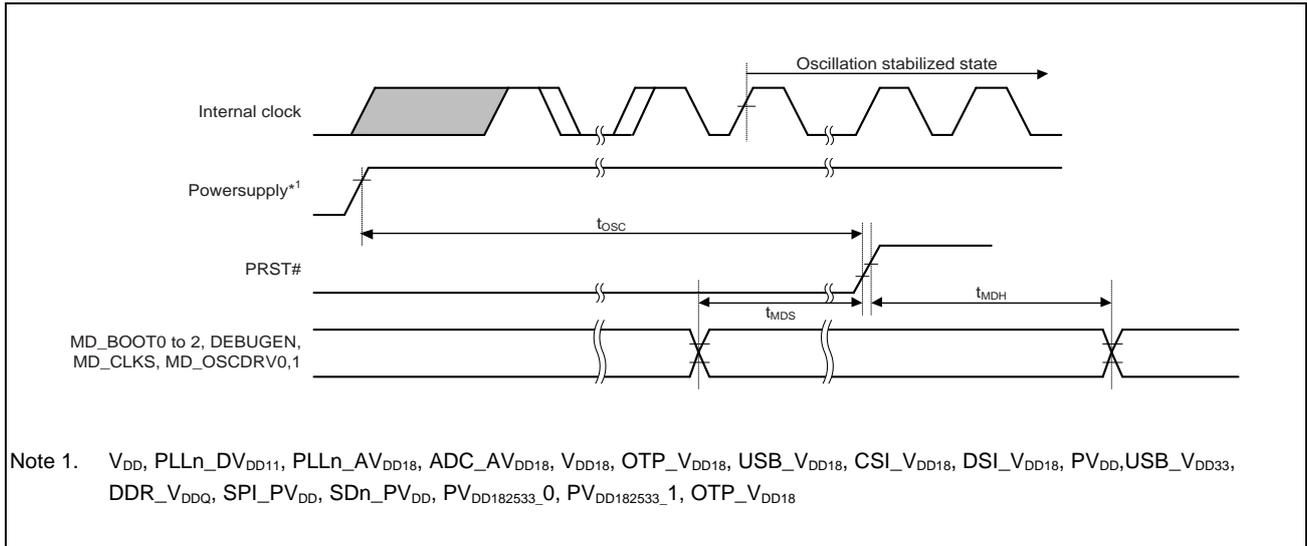
Figure 3.6   Power-On Oscillation Settling Time
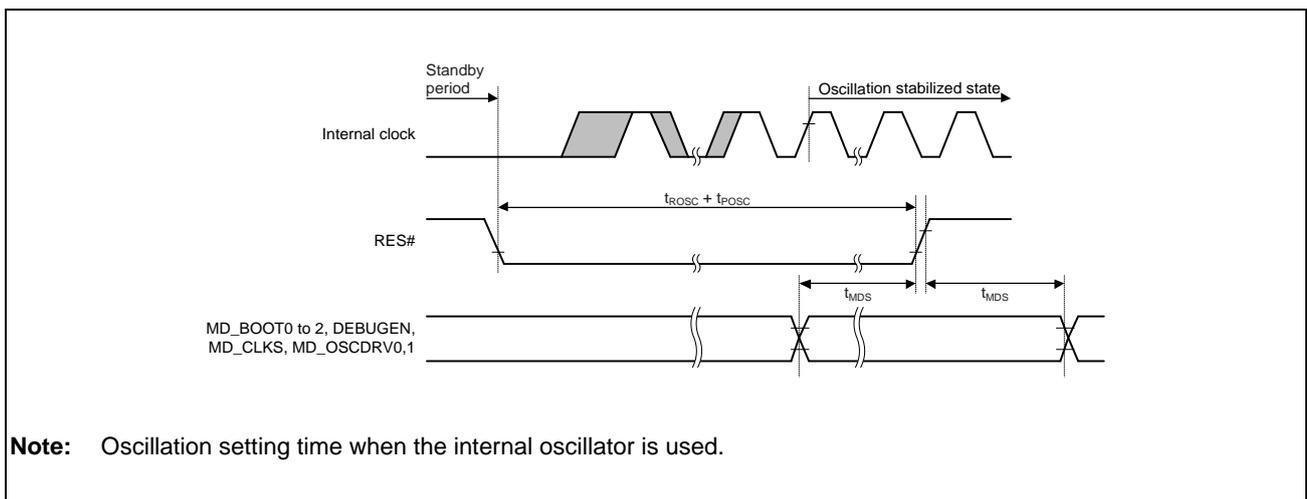
Figure 3.7   Oscillation Settling Time on Return from Standby (Return by Reset)

3.5.2   SDHI Access Timing

3.5.2.1   SDHI Access Timing (SDR 3.3-V)

Table 3.21   SDHC AC Access Timing (SDR at 3.3-V Operation)

Item	Symbol	Default Speed Mode (16.67 MHz)		High Speed Mode (33.33 MHz)		Unit	Figures
		Min.	Max.	Min.	Max.		
SD_CLK clock cycle	t_{SDCYC}	60.00	—	30.0	—	ns	**Figure 3.8**
SD_CLK clock high level width	t_{SDWH}	23.50	—	13.50	—	ns	
SD_CLK clock low level width	t_{SDWL}	23.50	—	13.50	—	ns	
SD_CLK clock rise time	t_{SDLH}	—	10	—	3	ns	
SD_CLK clock fall time	t_{SDHL}	—	10	—	3	ns	
SD_CMD,SD_DATA output delay	t_{SDODLY}	−4.50	4.0	−4.50	4.0	ns	
SD_CMD,SD_DATA input set up time	t_{SDIS}	5.5	—	5.5	—	ns	
SD_CMD,SD_DATA input hold time	t_{SDIH}	2.0	—	2.0	—	ns	
SD_CMD,SD_DATA input data width	t_{SDIDW}	—	—	—	—	ns	
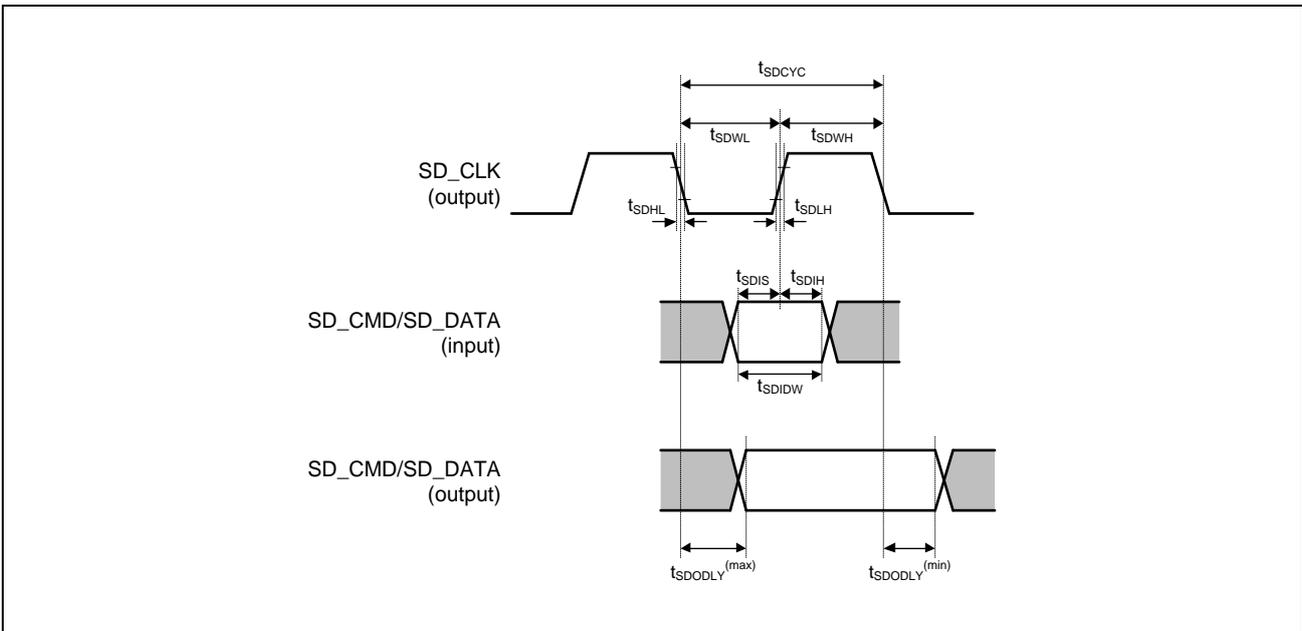
Figure 3.8   SDHC Interface Timing (SDR 3.3-V Power Supply)

NOTE

The disclosure of other characteristics of the SD interface needs the conclusion of the following agreement.

- SD Host/Ancillary Product License Agreement (SD HALA)

For details, contact your local sales representatives.

3.5.3   eMMC Access Timing

3.5.3.1   eMMC Host Interface Timing (Default)

Table 3.22   eMMC Host Interface Timing (MMC Default 3.3-V Power Supply)

Item	Symbol	Min.	Max.	Unit	Figures
SD0_CLK clock cycle	t_{MMCPP}	40.00	—	ns	**Figure 3.9**
SD0_CLK clock high level width	t_{MMCWH}	18.50	—	ns	
SD0_CLK clock low level width	t_{MMCWL}	18.50	—	ns	
SD0_CLK clock rise time	t_{MMCLH}	—	3	ns	
SD0_CLK clock fall time	t_{MMCHL}	—	3	ns	
SD0_CMD/SDDAT output delay	$t_{MMCODLY}$	−4.50	4.0	ns	
SD0_CMD/SDDAT input set up time	t_{MMCISU}	5.5	—	ns	
SD0_CMD/SDDAT input hold time	t_{MMCIH}	2.0	—	ns	
SD0_CMD/SDDAT input data width	t_{MMCIDW}	—	—	ns	

Table 3.23   eMMC Host Interface Timing (MMC Default 1.8-V Power Supply)

Item	Symbol	Min.	Max.	Unit	Figures
SD0_CLK clock cycle	t_{MMCPP}	40.00	—	ns	**Figure 3.9**
SD0_CLK clock high level width	t_{MMCWH}	19.25	—	ns	
SD0_CLK clock low level width	t_{MMCWL}	19.25	—	ns	
SD0_CLK clock rise time	t_{MMCLH}	—	2.45	ns	
SD0_CLK clock fall time	t_{MMCHL}	—	2.45	ns	
SD0_CMD/SDDAT output delay	$t_{MMCODLY}$	−2.00	2.50	ns	
SD0_CMD/SDDAT input set up time	t_{MMCISU}	4.00	—	ns	
SD0_CMD/SDDAT input hold time	t_{MMCIH}	1.40	—	ns	
SD0_CMD/SDDAT input data width	t_{MMCIDW}	—	—	ns	

3.5.3.2   eMMC host interface timing (HS-SDR)

Table 3.24   eMMC Host Interface Timing (MMC HS-SDR 3.3-V Power Supply)

Item	Symbol	Min.	Max.	Unit	Figures
SD0_CLK clock cycle	t_{MMCPP}	30.00	—	ns	**Figure 3.9**
SD0_CLK clock high level width	t_{MMCWH}	13.50	—	ns	
SD0_CLK clock low level width	t_{MMCWL}	13.50	—	ns	
SD0_CLK clock rise time	t_{MMCLH}	—	3	ns	
SD0_CLK clock fall time	t_{MMCHL}	—	3	ns	
SD0_CMD/SDDAT output delay	$t_{MMCODLY}$	−4.50	4.0	ns	
SD0_CMD/SDDAT input set up time	t_{MMCISU}	5.5	—	ns	
SD0_CMD/SDDAT input hold time	t_{MMCIH}	2.0	—	ns	
SD0_CMD/SDDAT input data width	t_{MMCIDW}	—	—	ns	

Table 3.25   eMMC Host Interface Timing (MMC HS-SDR 1.8-V Power Supply)

Item	Symbol	Min.	Max.	Unit	Figures
SD0_CLK clock cycle	t_{MMCPP}	20.00	—	ns	**Figure 3.9**
SD0_CLK clock high level width	t_{MMCWH}	9.25	—	ns	
SD0_CLK clock low level width	t_{MMCWL}	9.25	—	ns	
SD0_CLK clock rise time	t_{MMCLH}	—	2.45	ns	
SD0_CLK clock fall time	t_{MMCHL}	—	2.45	ns	
SD0_CMD/SDDAT output delay	$t_{MMCODLY}$	−2.00	2.50	ns	
SD0_CMD/SDDAT input set up time	t_{MMCISU}	4.00	—	ns	
SD0_CMD/SDDAT input hold time	t_{MMCIH}	1.40	—	ns	
SD0_CMD/SDDAT input data width	t_{MMCIDW}	—	—	ns	

Figure 3.9   eMMC Host Interface Timing (MMC Default/HS-SDR 1.8-V/3.3-V Power Supply)

3.5.3.3   eMMC host interface timing (HS200)

Table 3.26   eMMC Host Interface Timing (HS200 1.8-V Power Supply Operation, Output Load 15 pF)

Item	Symbol	Min.	Max.	Unit	Figures
SD0_CLK clock cycle	t_{MMCPP}	7.50	15.0	ns	**Figure 3.10**
SD0_CLK clock high level width	t_{MMCWH}	3.20	—	ns	
SD0_CLK clock low level width	t_{MMCWL}	3.20	—	ns	
SD0_CLK clock rise time	t_{MMCLH}	—	1.22	ns	
SD0_CLK clock fall time	t_{MMCHL}	—	1.22	ns	
SD0_CMD/SDDAT output delay	$t_{MMCODLY}$	−1.50	1.75	ns	
SD0_CMD/SDDAT input set up time	t_{MMCISU}	—	—	ns	
SD0_CMD/SDDAT input hold time	t_{MMCIH}	—	—	ns	
SD0_CMD/SDDAT input data width	t_{MMCIDW}	4.31	—	ns	
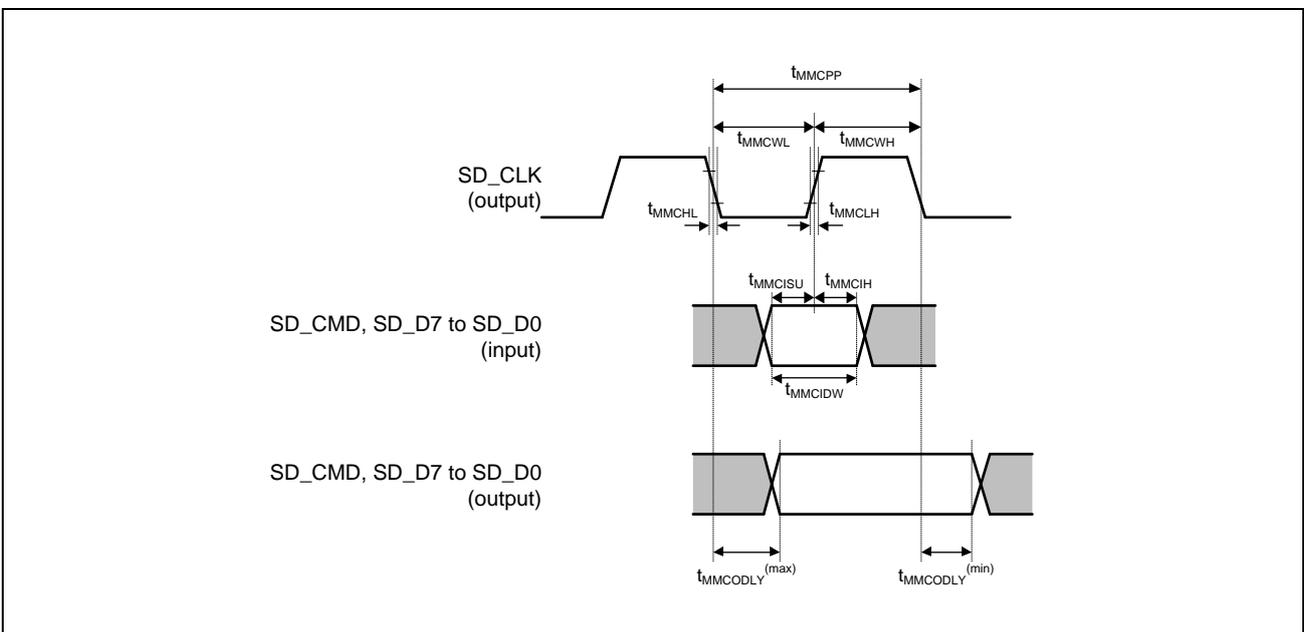
Figure 3.10   eMMC Host Interface (MMC Interface HS200 Mode 1.8-V Power Supply Selection)

3.5.4   CRU Access Timing

Table 3.27   CRU AC Access Timing

Item	Symbol	Min.	Max.	Unit	Figures
CAM_PCLK clock input cycle time	t_{CCYC}	9.2	74	ns	**Figure 3.11**
CAM_PCLK clock input rise time	t_{CR}	—	1	ns	
CAM_PCLK clock input low level pulse width	t_{CLW}	0.4	0.6	t_{CCYC}	
CAM_PCLK clock input high level pulse width	t_{CHW}	0.4	0.6	t_{CCYC}	
CAM_DATA0-15, CAM_HREF, CAM_VSYNC, CAM_FIELD setup time (P42_4 input)	t_{CSU1}	2	—	ns	
CAM_FIELD setup time (P3_1 input)	t_{CSU2}	4	—	ns	
CAM_DATA0-15, CAM_HREF, CAM_VSYNC, CAM_FIELD hold time	t_{CHD}	2	—	ns	
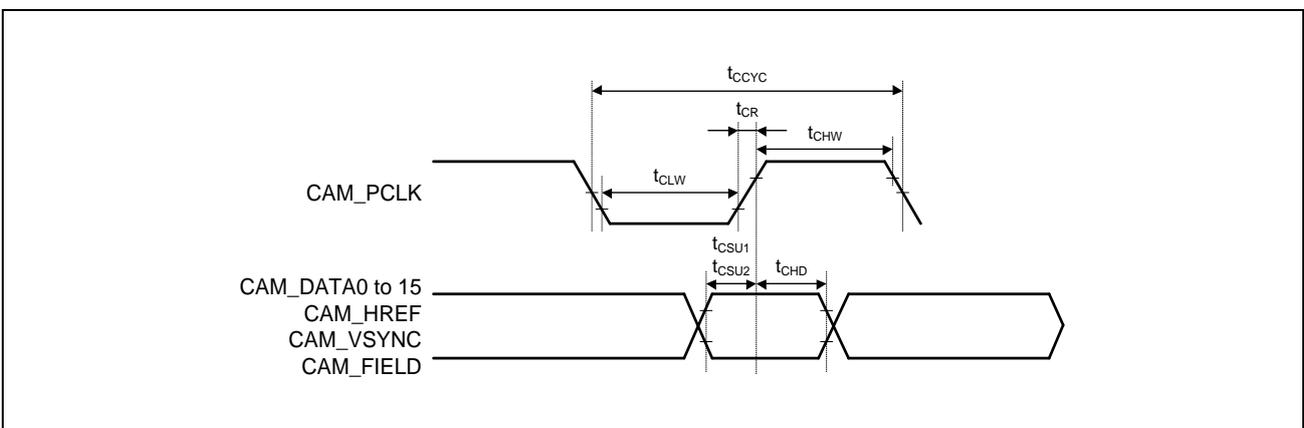
Figure 3.11   CRU AC Access Timing

3.5.5   LCDC Access Timing

Table 3.28   LCDC AC Access Timing

Item	Symbol	Min.	Max.	Unit	Figures
DCLK period	t_{Lcyc}	11.5	172.33	ns	**Figure 3.12**
DCLK low pulse width	t_{LOL}	$t_{Lcyc}/2 - 1.06$	$t_{Lcyc}/2 + 1.06$	ns	
DCLK high pulse width	t_{LOH}	$t_{Lcyc}/2 - 1.06$	$t_{Lcyc}/2 + 1.06$	ns	
DCLK rise time	t_{LOR}	—	3	ns	
DCLK fall time	t_{LOF}	—	3	ns	
Data output dealy	t_{DD}	−1.5	1.5	ns	

Note: AC access timing condition: SR = 1 (fast) / Drive capacity setting 12 mA / Load capacity 30 pF.
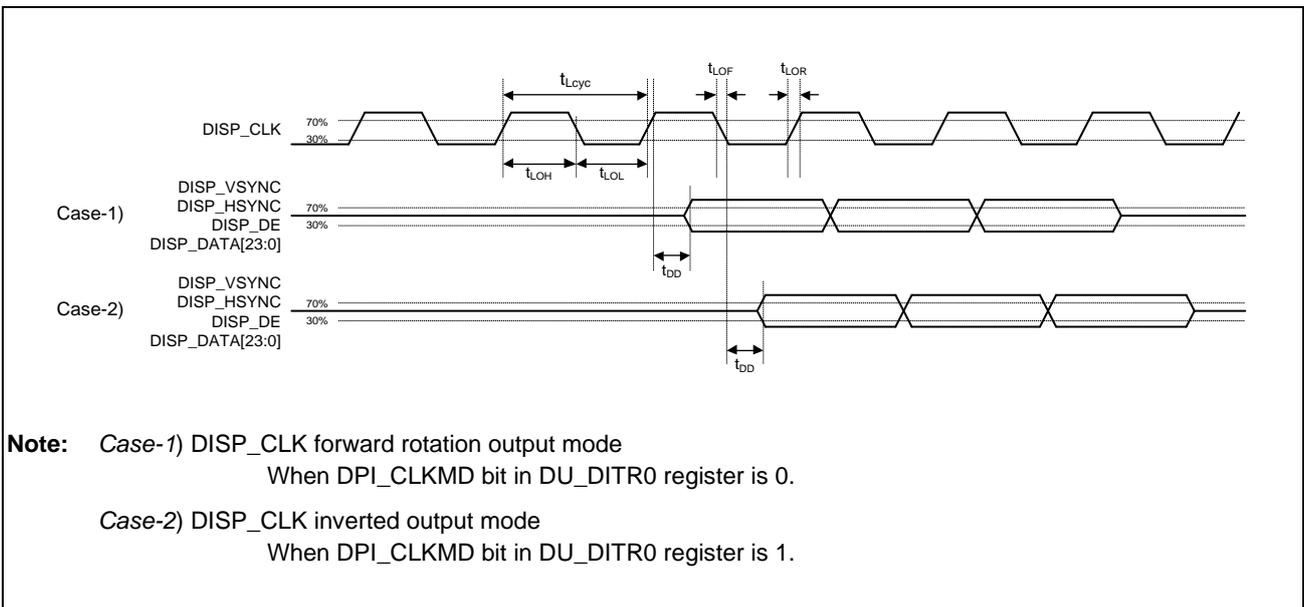
Note: *Case-1*) DISP_CLK forward rotation output mode
             When DPI_CLKMD bit in DU_DITR0 register is 0.

   Case-2) DISP_CLK inverted output mode
             When DPI_CLKMD bit in DU_DITR0 register is 1.

Figure 3.12   LCDC AC Access Timing

3.5.6 USB 2.0 Host/Function Module Access Timing

3.5.6.1 USB 2.0 Low-Speed Access Timing

Table 3.29   USB Transceiver Timing (Low-Speed)

Item	Symbol	Min.	Max.	Unit	Figures
Rise time	t_{LR}	75	300	ns	**Figure 3.13**
Fall time	t_{LF}	75	300	ns	
Rise/fall time lag	t_{LR}/t_{LF}	80	125	%	
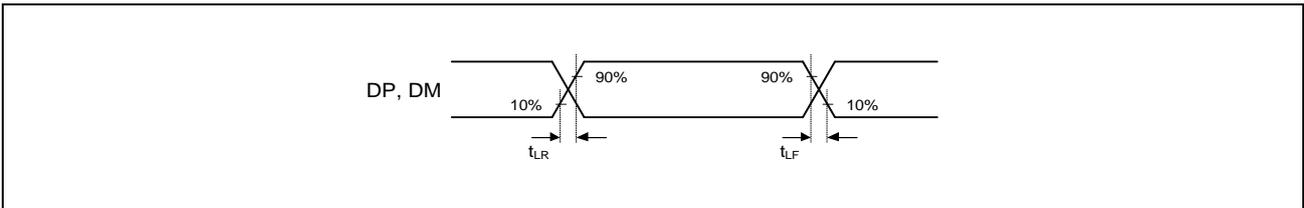
Figure 3.13   USB0_DP, USB1_DP, USB0_DM, and USB1_DM Output Timing (Low-Speed)
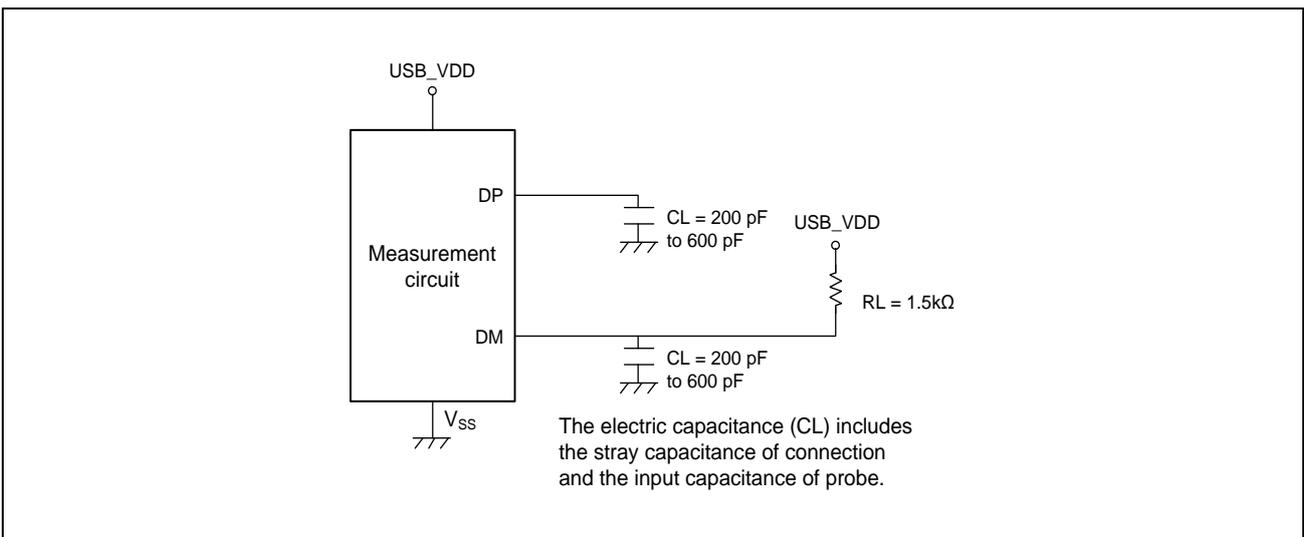
Figure 3.14   Measurement Circuit (Low-Speed)

3.5.6.2   USB 2.0Full-Speed Access Timing

Table 3.30   USB Transceiver Timing (Full-Speed)

Item	Symbol	Min.	Max.	Unit	Figures
Rise time	t_{FR}	4	20	ns	**Figure 3.15**
Fall time	t_{FF}	4	20	ns	
Rise/fall time lag	t_{FR}/t_{FF}	90	111.11	%	
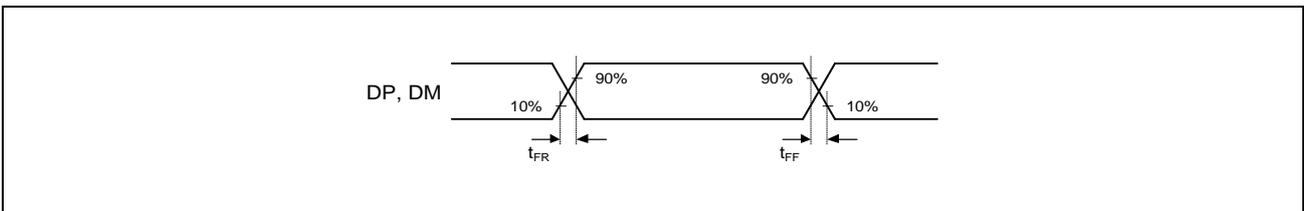
Figure 3.15   USB0_DP, USB1_DP, USB0_DM, and USB1_DM Output Timing (Full-Speed)
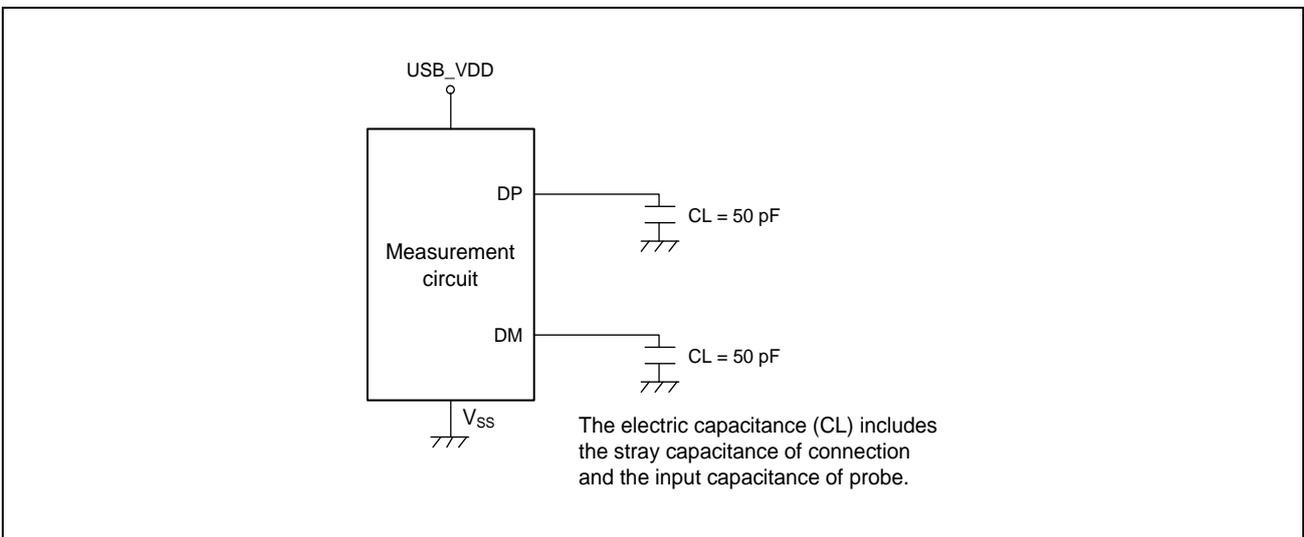
Figure 3.16   Measurement Circuit (Full-Speed)

3.5.6.3   USB 2.0 Hi-Speed Access Timing

Table 3.31   USB Transceiver Timing (Hi-Speed)

Item	Symbol	Min.	Max.	Unit	Figures
Rise edge rate	t_{HSR}	—	2133	V/μs	**Figure 3.17**
Fall edge rate	t_{HSF}	—	2133	V/μs	
Output driver resistance	Z_{HSDRV}	40.5	49.5	Ω	
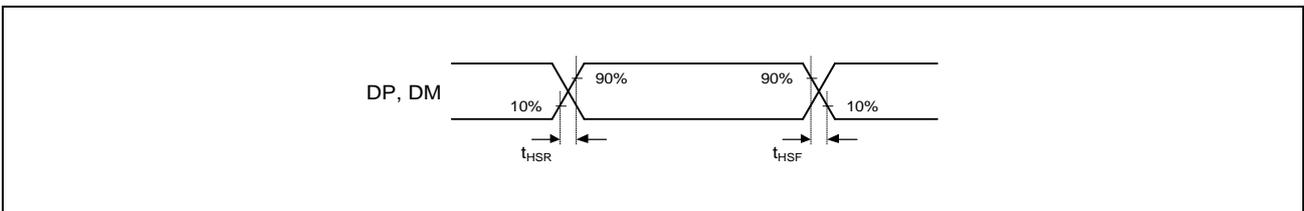
Figure 3.17   USB0_DP, USB1_DP, USB0_DM, and USB1_DM Output Timing (Hi-Speed)
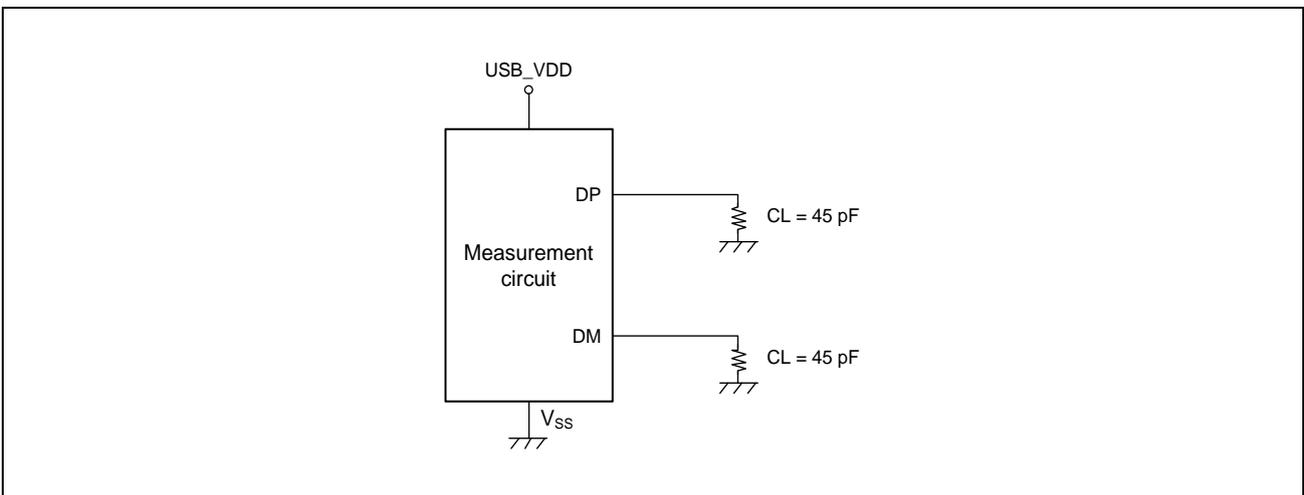
Figure 3.18   Measurement Circuit (Hi-Speed)

3.5.7   Ethernet Interface Access Timing

Table 3.32   Ethernet Interface Access Timing

Item	Symbol	Min.	Max.	Unit	Figures
MDC half cycle	t_{MDC}	0	300	ns	**Figure 3.19**
MDI setup time	$t_{MDIsetup}$	10	—	ns	
MDI hold time	$t_{MDIhold}$	10	—	ns	
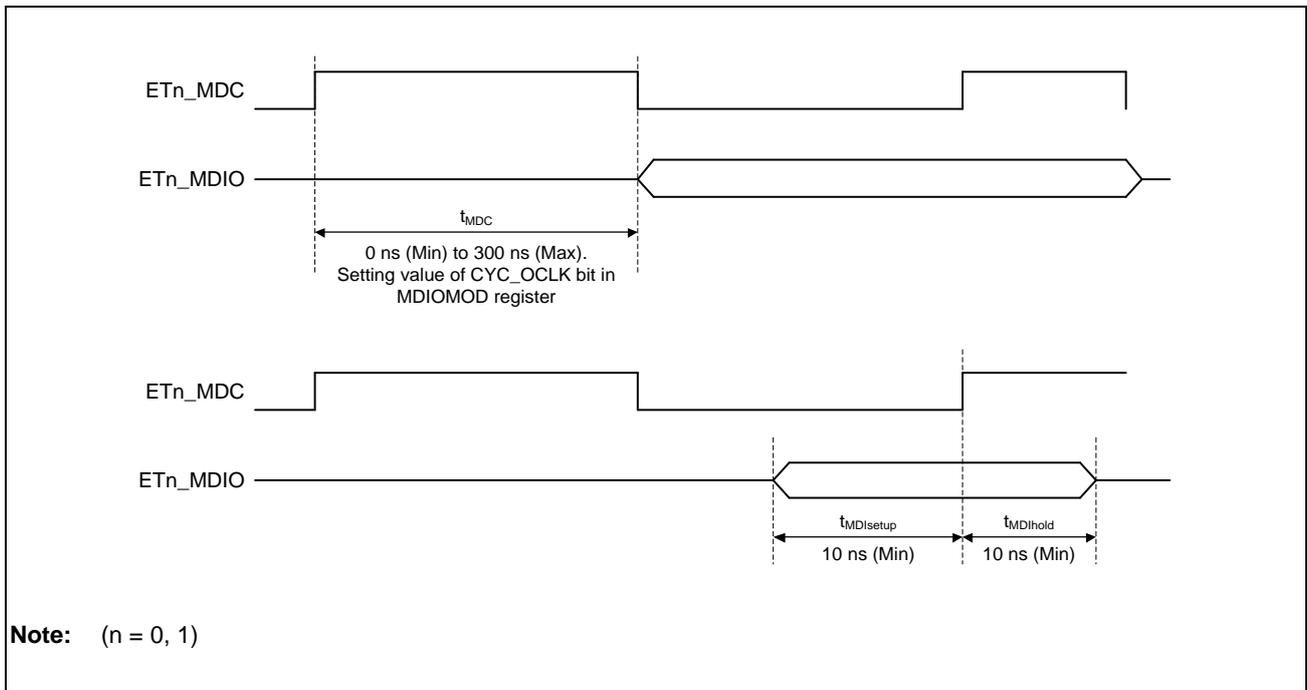
Figure 3.19   Management Interface

3.5.7.1   Ethernet-IF (Ether MII)

Table 3.33   Ethernet-IF Access Timing (Ether MII)

Item		Symbol	Min.	Max.	Unit	Figures
Ether MII	ETH_GTXTXC_TXC period	t_{Tcyc}	40	—	ns	**Figure 3.20**
	ETH_TXCTL output delay	t_{TENd}	0	25	ns	
	ETH_TXD3-0 output delay	t_{MTDd}	0	25	ns	
	ETH_RXC period	t_{Rcyc}	40	—	ns	
	ETH_RXDV setup time	t_{RDVs}	10	—	ns	
	ETH_RXDV hold time	t_{RDVh}	10	—	ns	
	ETH_RXD3-0 setup time	t_{MRDs}	10	—	ns	
	ETH_RXD3-0 hold time	t_{MRDh}	10	—	ns	
	ETH_RXER setup time	t_{RERs}	10	—	ns	
	ETH_RXER hold time	t_{RERh}	10	—	ns	

Note: I/O driving ability: 8 mA
CL = 8 pF
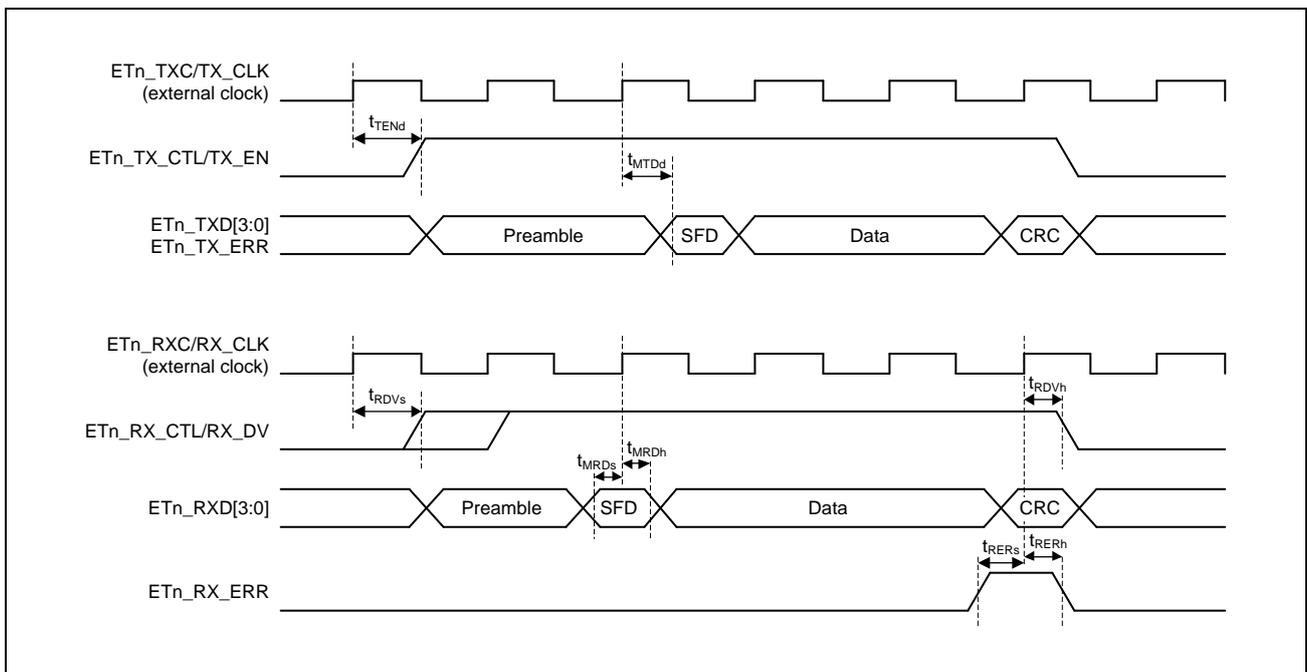
Figure 3.20   MII Transmission Timing

Validated with IEEE802.3 regulation.

The propagation delay for each twisted pair, measured from the MII connector to the PHY, shall not exceed 2.5 ns.

The variation in the propagation delay of the twisted pairs in a given cable bundle, measured from the MII connector to the PHY, shall not exceed 0.1 ns.

3.5.7.2   Ethernet-IF (Ether RGMII)

Table 3.34   Ethernet-IF Access Timing (Ether RGMII)

Item		Symbol	Min.	Typ.	Max.	Unit	capaci-tance	Remarks	Figures
Ether RGMII	Data to clock output skew @ transmitter	T_{skewT}	−500	0	500	ps	8 pF	Tx RGMII	**Figure 3.21**
	Data to clock input skew @ receiver	T_{skewR}	1	1.8	2.6	ns	8 pF		
	Data to clock output setup @ transmitter integrated delay	T_{setupT}	1.2	2.0	—	ns	8 pF	Rx RGMII-ID	**Figure 3.22**
	Clock to data output hold @ transmitter integrated delay	T_{holdT}	1.2	2.0	—	ns	8 pF		
	Data to clock input setup setup @ receiver integrated delay	T_{setupR}	1.0	2.0	—	ns	8 pF	Rx RGMII-ID	**Figure 3.22**
	Data to clock input setup hold @ receiver integrated delay	T_{holdR}	1.0	2.0	—	ns	8 pF		
	Clock cycle duration[1]	T_{cyc}	7.2	8	8.8	ns	8 pF	—	—
	Duty cycle for gigabit	Duty_G	45	50	55	%	8 pF		
	Duty cycle for 10/100T	Duty_T	40	50	60	%	8 pF		
	Rise/fall time (20-80%)	T_r/T_f	—	—	0.75	ns	8 pF		

Note 1.   For 10 Mbps and 100 Mbps, T_{cyc} will scale to 400ns ±40ns and 40ns ±4ns respectively.
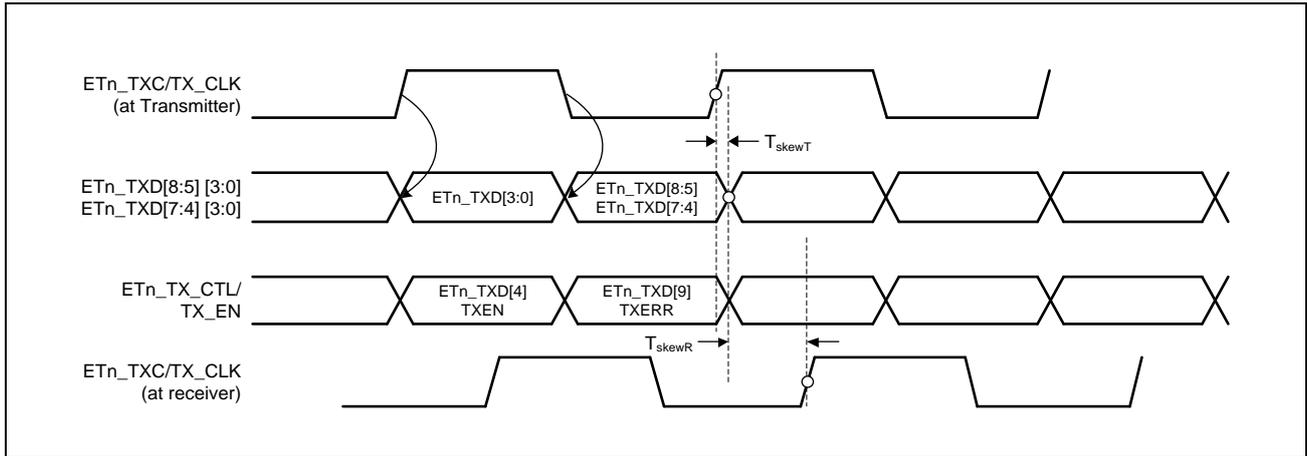
Figure 3.21   Multiplexing & Timing Diagram — RGMII (Transmitter)
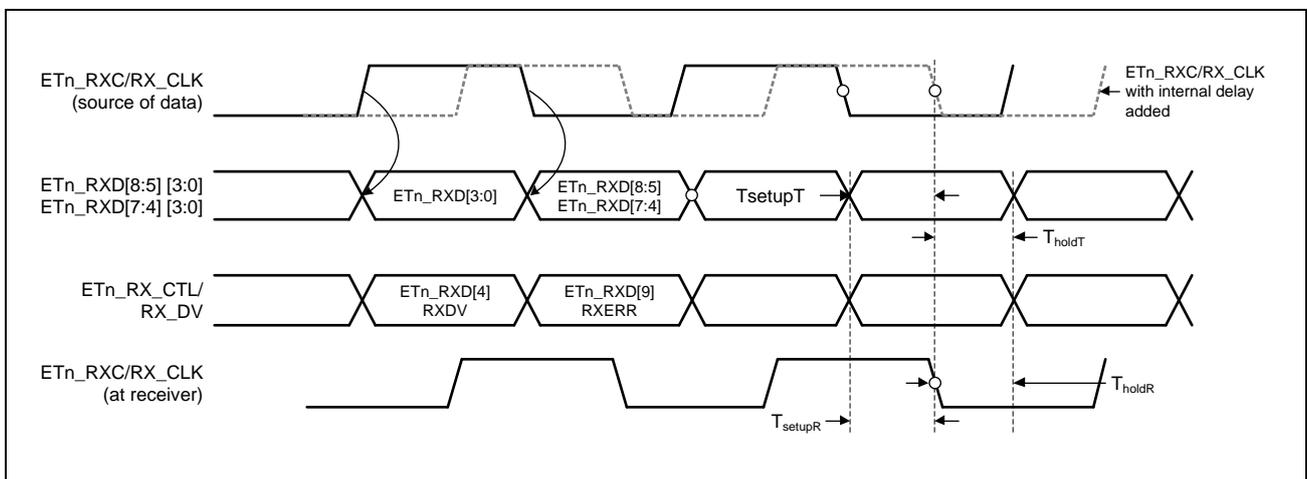
Figure 3.22   Multiplexing & Timing Diagram — RGMII-ID (Receiver)

3.5.8   JTAG Debugger Interface Access Timing

Table 3.35   Debugger IF Timing

Item	Symbol	Min.	Max.	Unit	Figures
TCK_SWCLK cycle time	t_{TCKcyc}	50	—	ns	**Figure 3.23**
TCK_SWCLK high pulse width	t_{TCKH}	20	—	ns	**Figure 3.24**
TCK_SWCLK low pulse width	t_{TCKL}	20	—	ns	
TDI setup time	t_{TDIS}	15	—	ns	
TDI hold time	t_{TDIH}	15	—	ns	
TMS_SWDIO setup time	t_{TMSS}	15	—	ns	
TMS_SWDIO hold time	t_{TMSH}	15	—	ns	
SWDIO delay time	t_{SWDO}	—	14	ns	
TDO delay time	t_{TDOD}	—	14	ns	
Capture register setup time	t_{CAPTS}	10	—	ns	**Figure 3.25**
Capture register hold time	t_{CAPTH}	10	—	ns	
Update register delay time	$t_{UPDATED}$	—	20	ns	
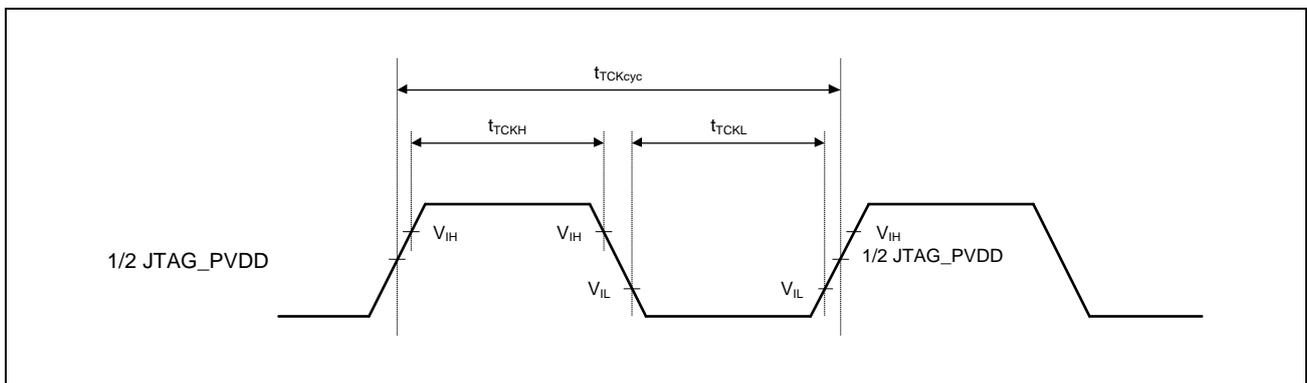
Figure 3.23   TCK_SWDCLK Input Timing
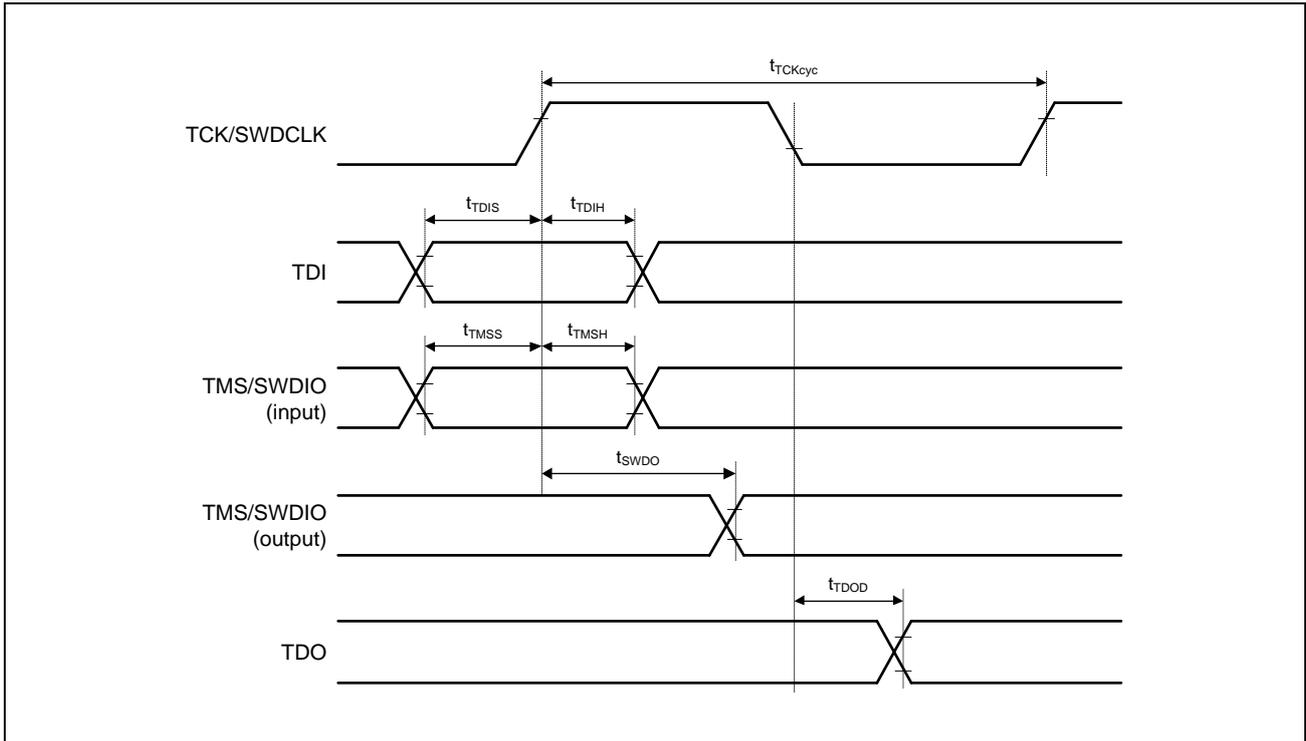
Figure 3.24   Data Transfer Timing
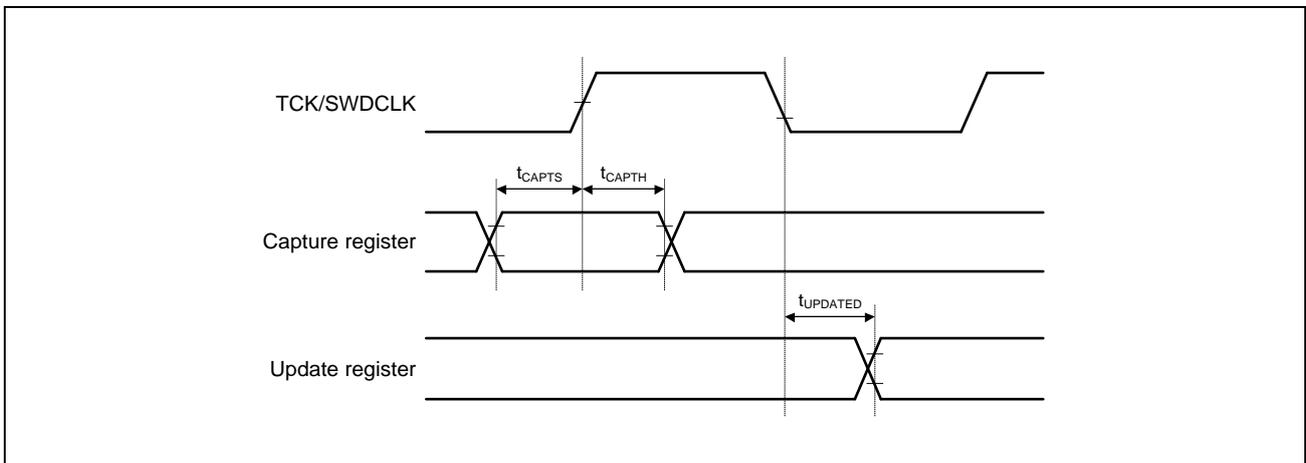
Figure 3.25   Boundary Scan Input/Output I/O Timing

3.5.9   SPI Multi I/O Bus Controller Access Timing

Table 3.36   SPI Multi I/O Bus Contoller Access Timing (1/2)

Item		Symbol	1.8 V (Serial flash/octal-SPI flash/hyper flash connected) Min.	Max.	3.3 V (Serial flash connected) Min.	Max.	Unit	Figures
Clock cycle		t_{SPBcyc}	10.0	—	15.0	—	ns	**Figure 3.26**, **Figure 3.30**
CLK high pulse width		t_{SPBWH}	0.45	0.55	0.45	0.55	t_{SPBcyc}	**Figure 3.26**, **Figure 3.30**
CLK low pulse width		t_{SPBWL}	0.45	0.55	0.45	0.55	t_{SPBcyc}	**Figure 3.26**, **Figure 3.30**
CLK rise time		t_{SPBR}	—	1.0	—	3.2	ns	**Figure 3.26**, **Figure 3.30**
CLK fall time		t_{SPBF}	—	1.0	—	3.2	ns	**Figure 3.26**, **Figure 3.30**
Data input setup time	QSPI0_SPCLK base point (SDR mode timing adjusted)	t_{SU}	6.7	—	7.5	—	ns	**Figure 3.27**
	QSPI0_SPCLK base point (DDR mode timing adjusted)		4.5	—	4.5	—	ns	**Figure 3.28**
	QSPI1_SSL base point (DQS base point)		−0.9[2]	—	—	—	ns	**Figure 3.31**
Data input hold time	QSPI0_SPCLK base point (SDR mode timing adjusted)	t_H	0.5	—	0.5	—	ns	**Figure 3.27**
	QSPI0_SPCLK base point (DDR mode timing adjusted)		1.0	—	1.0	—	ns	**Figure 3.28**
	QSPI1_SSL base point (DQS base point)		2.69[2]	—	—	—	ns	**Figure 3.31**
SSL setup time		t_{LEAD}	$1.5 \times t_{SPBcyc} - 3$	$8.5 \times t_{SPBcyc} + 3$	$1.5 \times t_{SPBcyc} - 3$	$8.5 \times t_{SPBcyc} + 3$	ns	**Figure 3.27**, **Figure 3.28**, **Figure 3.31**
SSL hold time		t_{LAG}	$1 \times t_{SPBcyc} - 3$	$8 \times t_{SPBcyc} + 3$	$1 \times t_{SPBcyc} - 3$	$8 \times t_{SPBcyc} + 3$	ns	**Figure 3.27**, **Figure 3.28**, **Figure 3.31**
Continuous transfer delay time		t_{TD}	$1 \times t_{SPBcyc} - 3$	$8 \times t_{SPBcyc} + 3$	$1 \times t_{SPBcyc} - 3$	$8 \times t_{SPBcyc} + 3$	ns	**Figure 3.27**, **Figure 3.28**, **Figure 3.31**
Data output delay time	SDR	t_{OD}	—	2.0	—	5.0	ns	**Figure 3.27**
	DDR		—	6.5[2]	—	7.5[3]	ns	**Figure 3.28**
	Hyper/octal		—	2.8	—	—	ns	**Figure 3.31**
Data output hold time	SDR	t_{OH}	−2.0	—	-5.0	—	ns	**Figure 3.27**
	DDR		1.0[2]	—	2.1[3]	—	ns	**Figure 3.28**
	Hyper/octal		0.9	—	—	—	ns	**Figure 3.31**
Skew of Clock to Data Strobe		t_{CKDS}	—	7.0	—	—	ns	**Figure 3.31**

Table 3.36   SPI Multi I/O Bus Conttoller Access Timing (2/2)

Item		Symbol	1.8 V (Serial flash/octal-SPI flash/hyper flash connected)		3.3 V (Serial flash connected)		Unit	Figures
			Min.	Max.	Min.	Max.		
Data output buffer off time	SDR	t_{BOFF}	—	2.0	—	3.0	ns	**Figure 3.29**
	DDR		—	2.0	—	3.0	ns	**Figure 3.29**
AC differential crossing voltage		V_{OX}	PVcc_SPI × 0.4	PVcc_SPI × 0.6	—	—	V	**Figure 3.30**

Note 1.   Output load: 15 pF/driving ability: 12 mA

Note 2.   QSPI0_SPCLK frequency: 100 MHz.

Note 3.   QSPI0_SPCLK frequency: 66 MHz
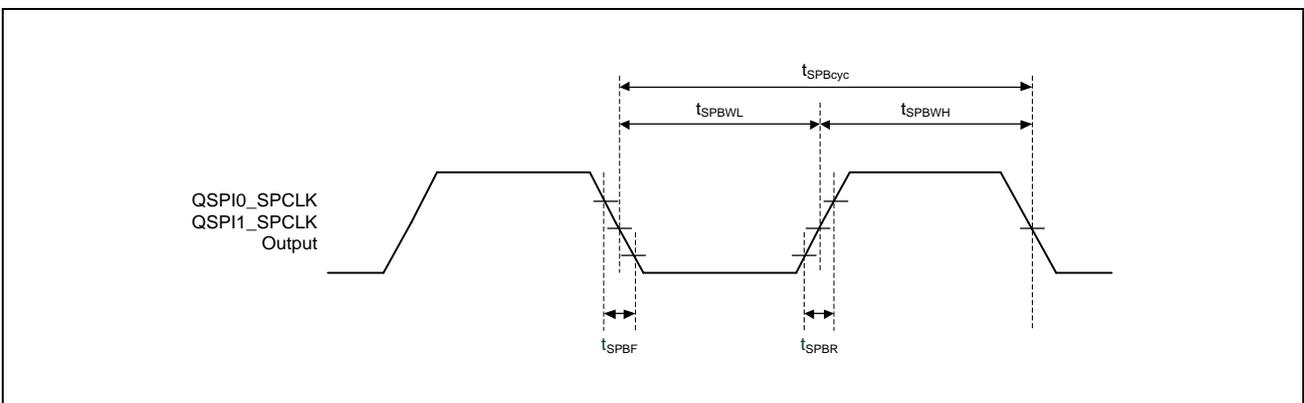
Figure 3.26   Clock Timing
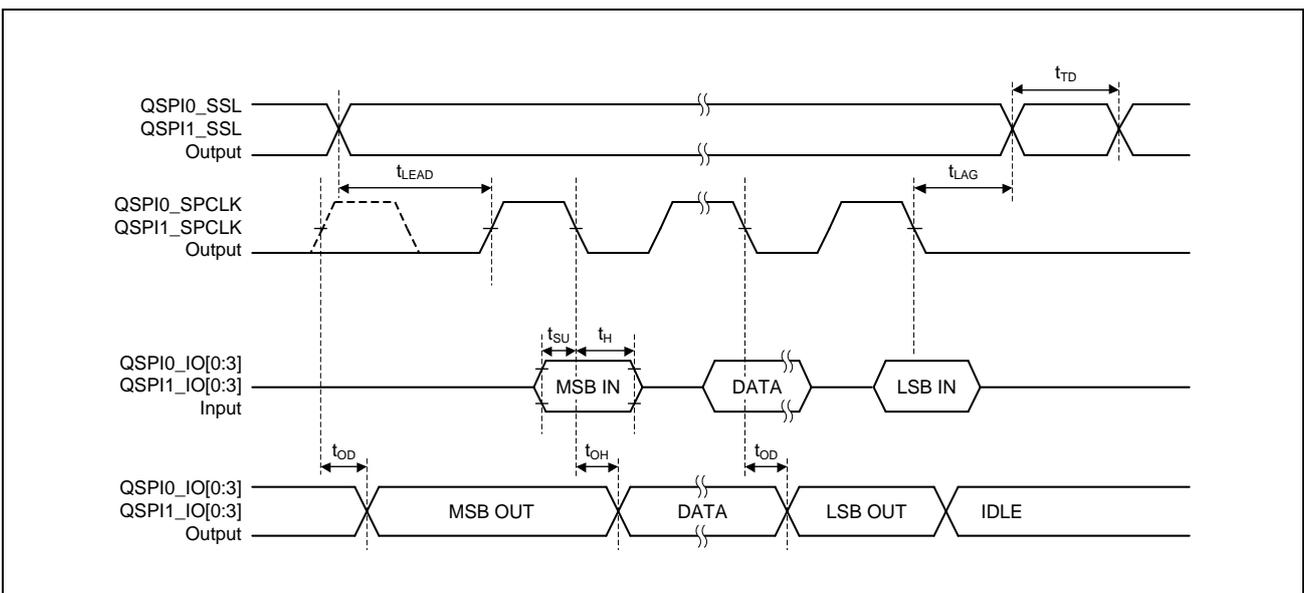
Figure 3.27   SDR Transfer Format Transmission and Reception Timing
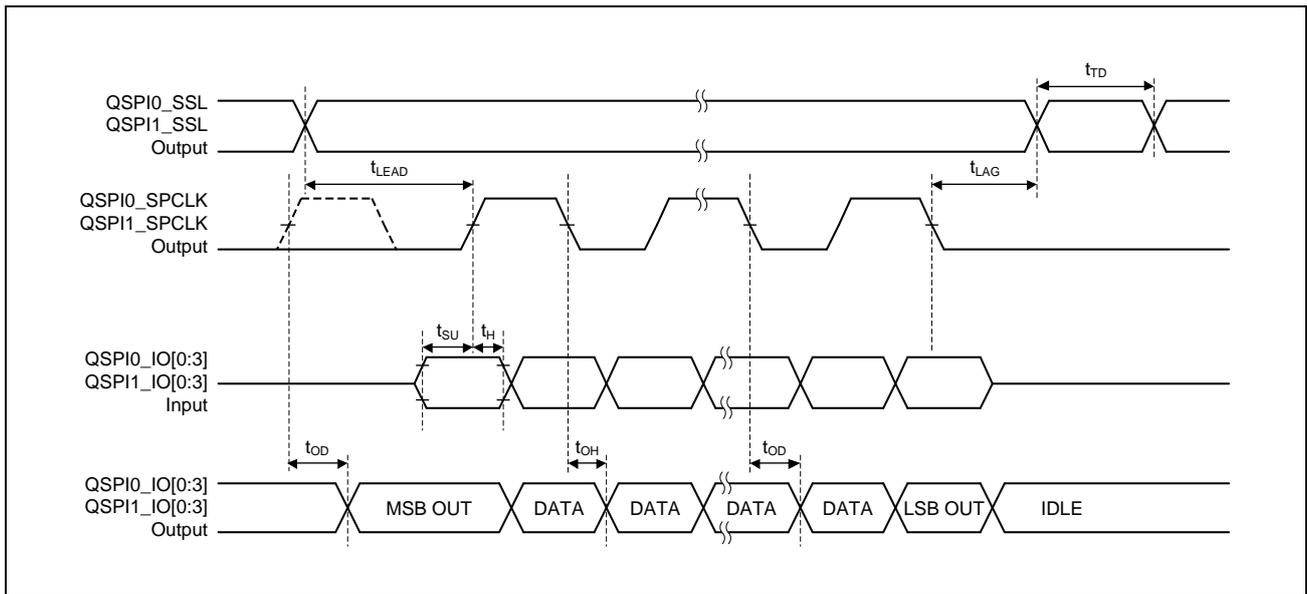
Figure 3.28   DDR Transfer Format Transmission and Reception Timing
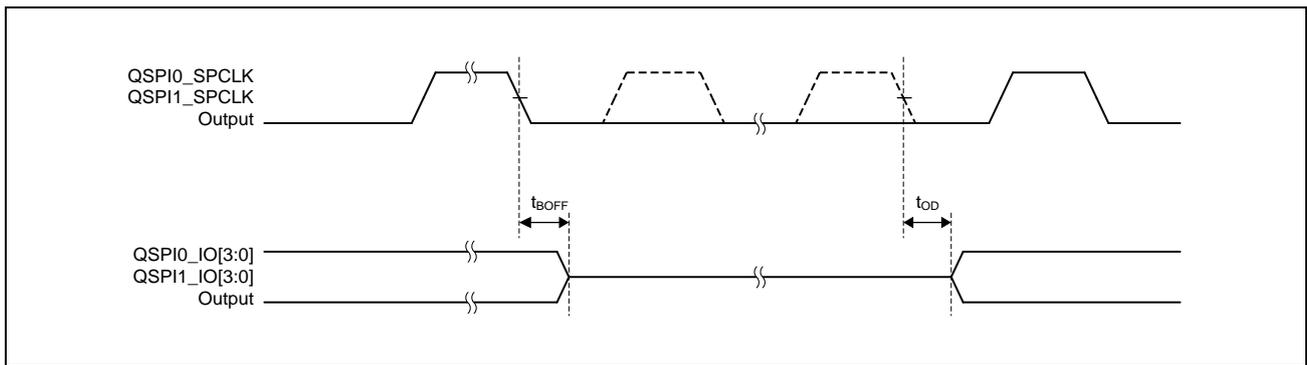
Figure 3.29   Timing for Switching the Buffers On and Off
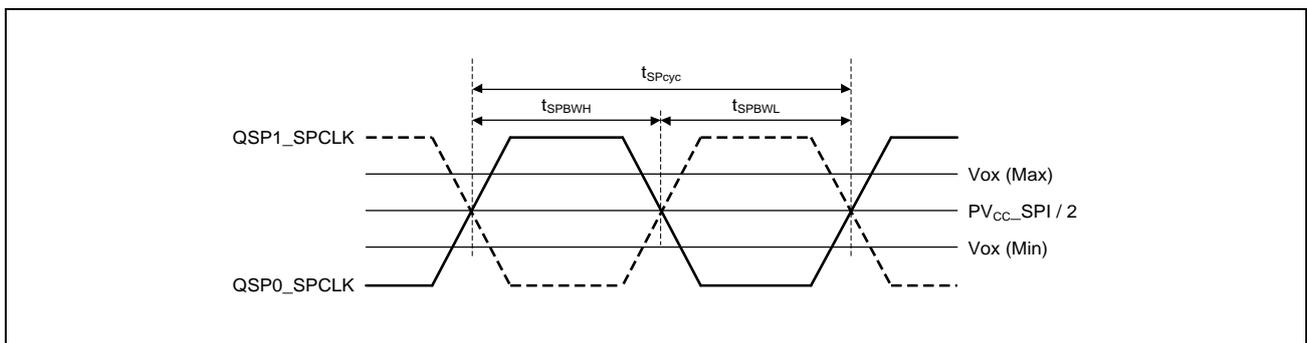
Figure 3.30   AC Differential Crossing Voltage
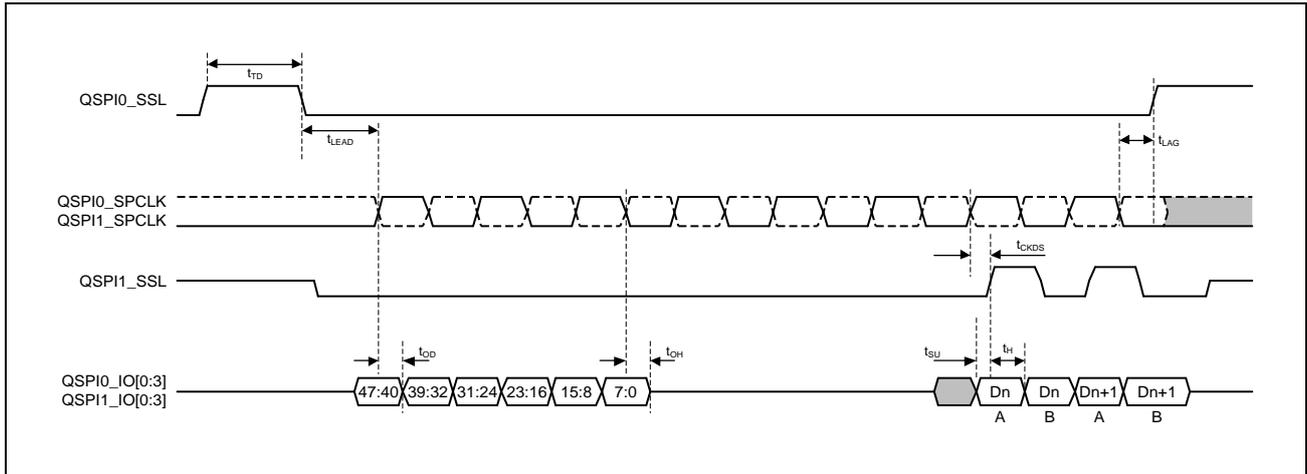
Figure 3.31   Transmit/Receive Timing with Octal-SPI Flash Memory or HyperFlash™ Connected

3.5.10   Control Signal Access Timing

Table 3.37   Control Signal Timing

Item	Symbol	Min.	Max.	Unit	Figures
PRST# pulse width	t_{RESW}	20	—	t_{cyc}[1]	**Figure 3.32**
TRST# pulse width	t_{TRSW}	20	—	t_{cyc}[1]	
NMI pulse width	t_{NMIW}	20	—	t_{cyc}[1]	**Figure 3.34**
IRQ pulse width	t_{IRQW}	20	—	t_{cyc}[1]	
TINT pulse width	t_{TINTW}	20	—	t_{cyc}[1]	
PRST# input rise time	t_{RSr}	—	500	µs	**Figure 3.33**

Note 1. t_{cyc} = 41.666 ns (24 MHz)
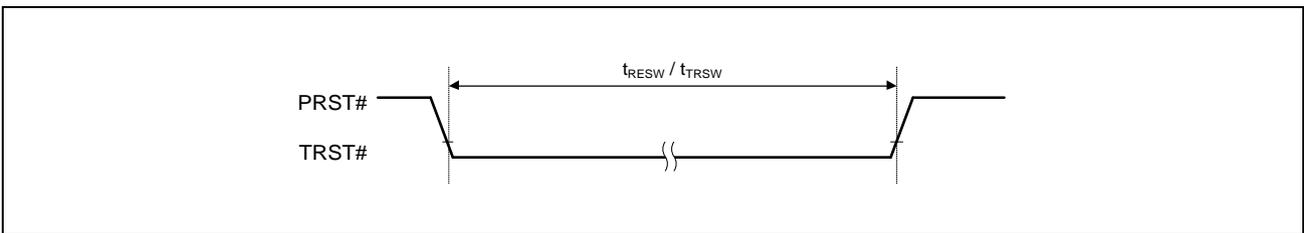
Figure 3.32   Reset Input Timing 1
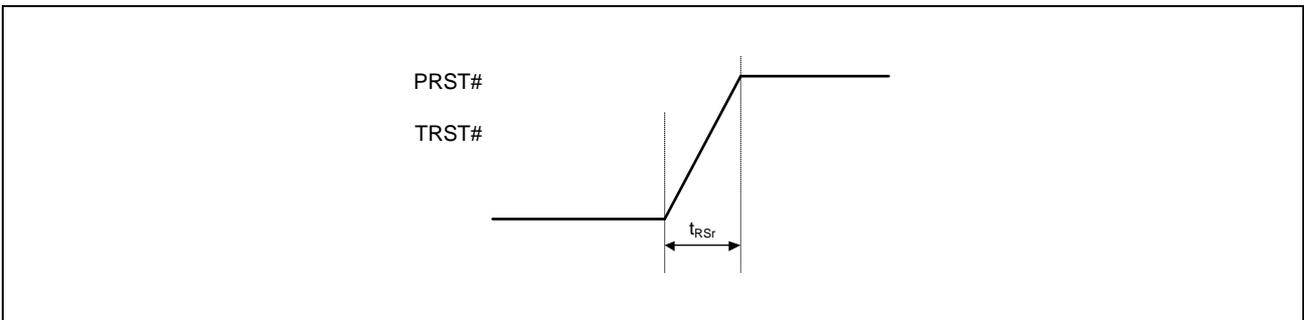
Figure 3.33   Reset Input Timing 2

Note: This specification "(Min. 20 t_{cycle})" is the min. pulse width the case that the digital noise filter is off. For details on digital noise filter settings, refer to *Section 41, General Purpose Input Output Port (GPIO)*, in the *User's Manual: Hardware*.
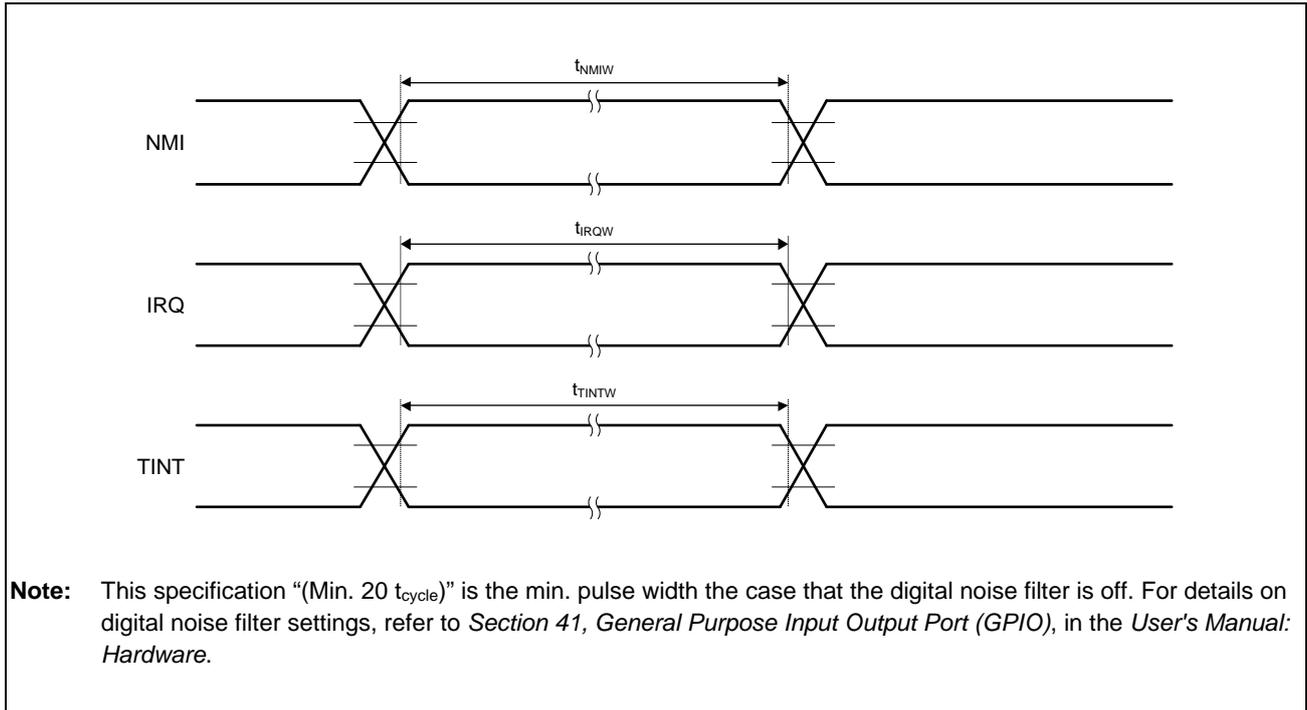
Figure 3.34   Interrupt Signal Input Timing

3.5.11   Serial Sound Interface (SSIF-2) Access Timing

Table 3.38   SSIF-2 Timing

Item	I/O	Symbol	Min.	Max.	Unit	Figures
Output clock cycle	Output	t_O	80	64000	ns	**Figure 3.35**
Input clock cycle	Input	t_I	80	—	ns	
Clock high	Bidirectional	t_{HC}	32	—	ns	
Clock low		t_{LC}	32	—	ns	
Clock rise time/clock fall time	Output	t_{RC}/t_{FC}	—	25	ns	
Setup time	Input	t_{SR}	25	—	ns	**Figure 3.36**, **Figure 3.37**, **Figure 3.38**
Hold time		t_{HR}	5	—	ns	
SILRCK output delay time	Output	t_{DTR}	−5	25	ns	
Data output delay time (Noise canceler not in use)		t_{DTR}	−5	25	ns	
Data output delay time (Noise canceler in use)		t_{DTR}	10	50	ns	

Note: AC access timing condition: drive ability 12mA, output load 30pF, slew rate = fast
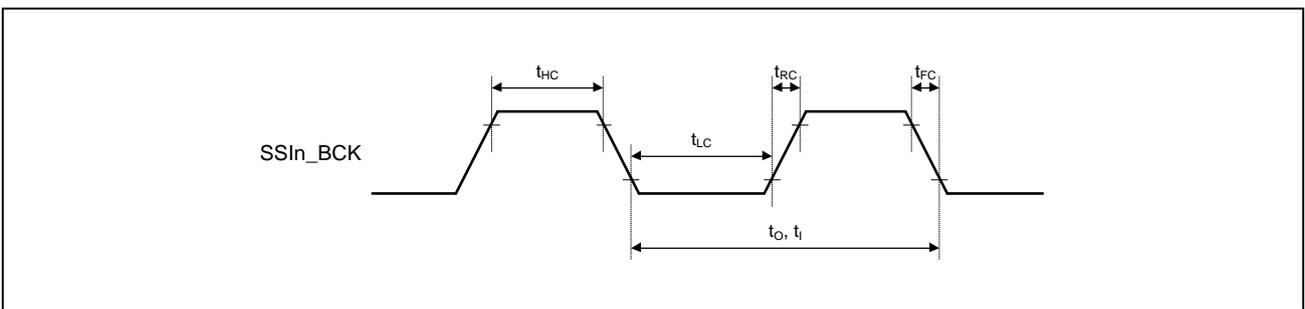
Figure 3.35   Bit Clock Input/Output Timing
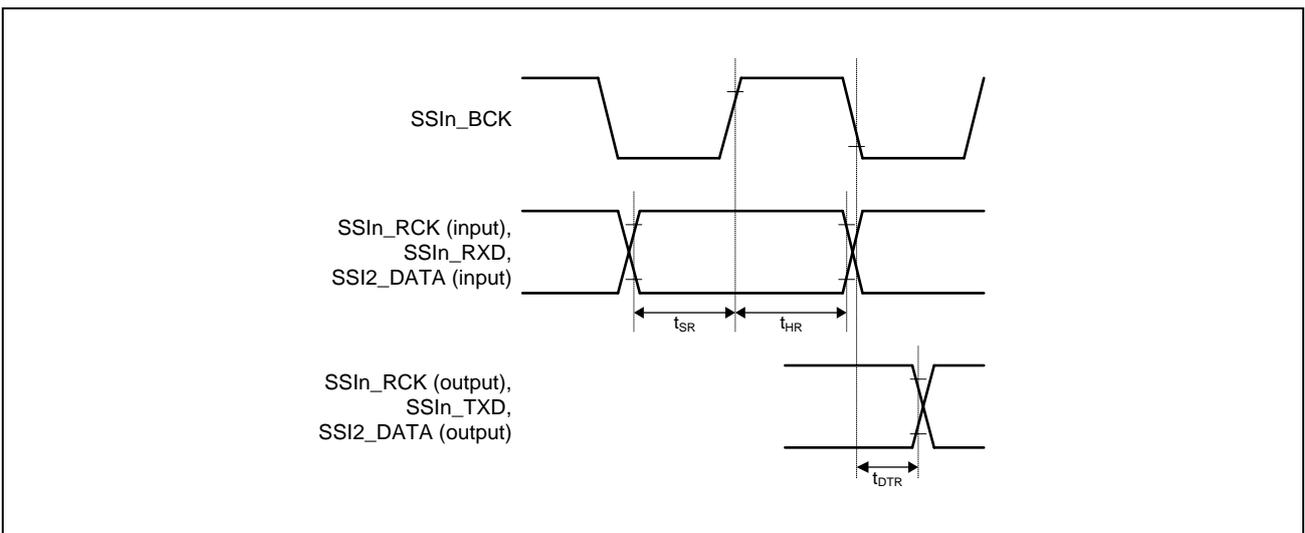
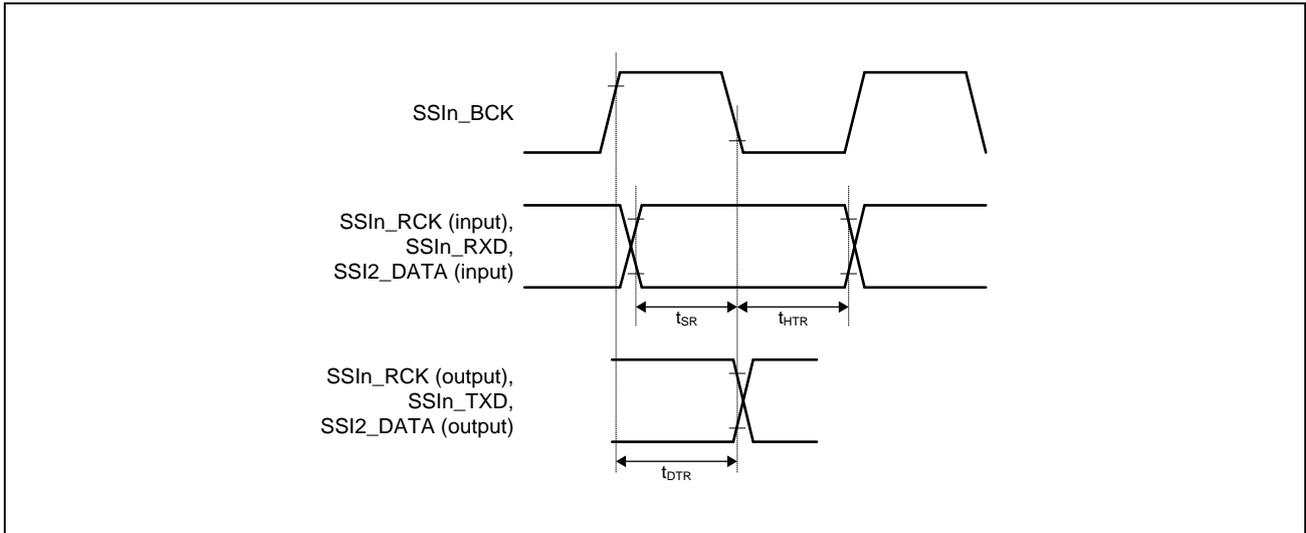Figure 3.36   Transmission and Reception Timing (SSIBCK Falling Output)

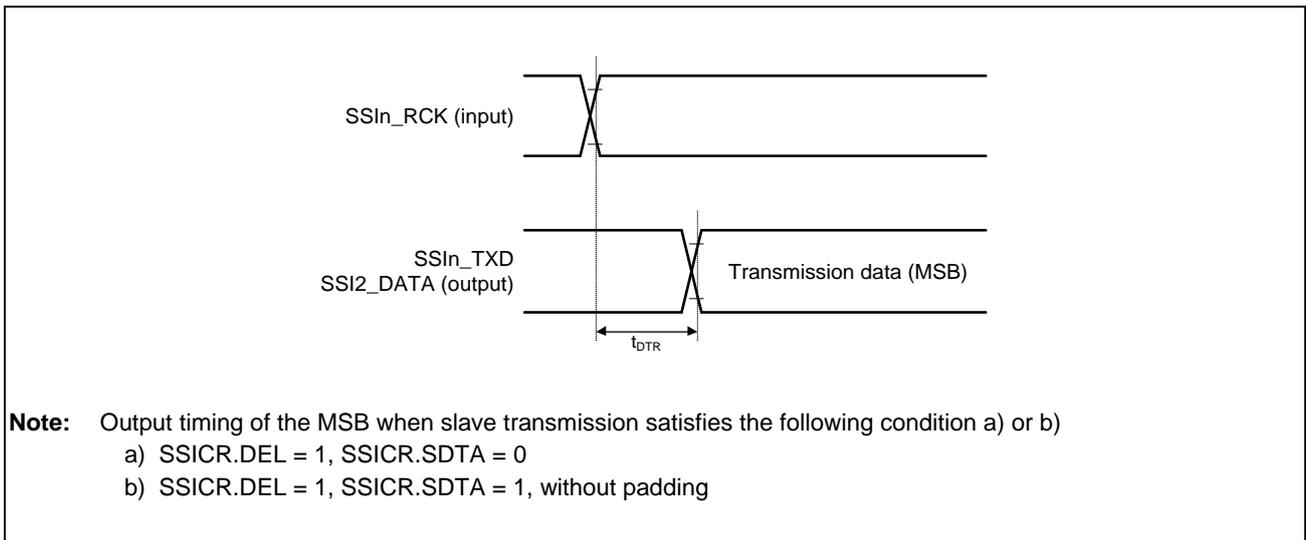Figure 3.37   Transmission and Reception Timing (SSIBCK Rising Output)

Note: Output timing of the MSB when slave transmission satisfies the following condition a) or b)
        a) SSICR.DEL = 1, SSICR.SDTA = 0
        b) SSICR.DEL = 1, SSICR.SDTA = 1, without padding

Figure 3.38   Transmission Timing (Slave, in Synchronization with SSILRCK)

3.5.12   CAN-FD Interface Access Timing

Table 3.39   CAN-FD Interface Timing

Item	Symbol	CAN		CAN-FD		Unit	Figures
		Min.	Max.	Min.	Max.		
Internal delay time	t_{node} [*1]	—	100	—	75	ns	**Figure 3.39**
Transmission rate	—	—	1	—	4	Mbps	

Note: AC access timing condition: drive ability 12mA, output load 15pF, slew rate = fast

Note 1.   Internal delay time (t_{node}) = Internal transfer delay time (t_{output}) + Internal receive delay time (t_{input})
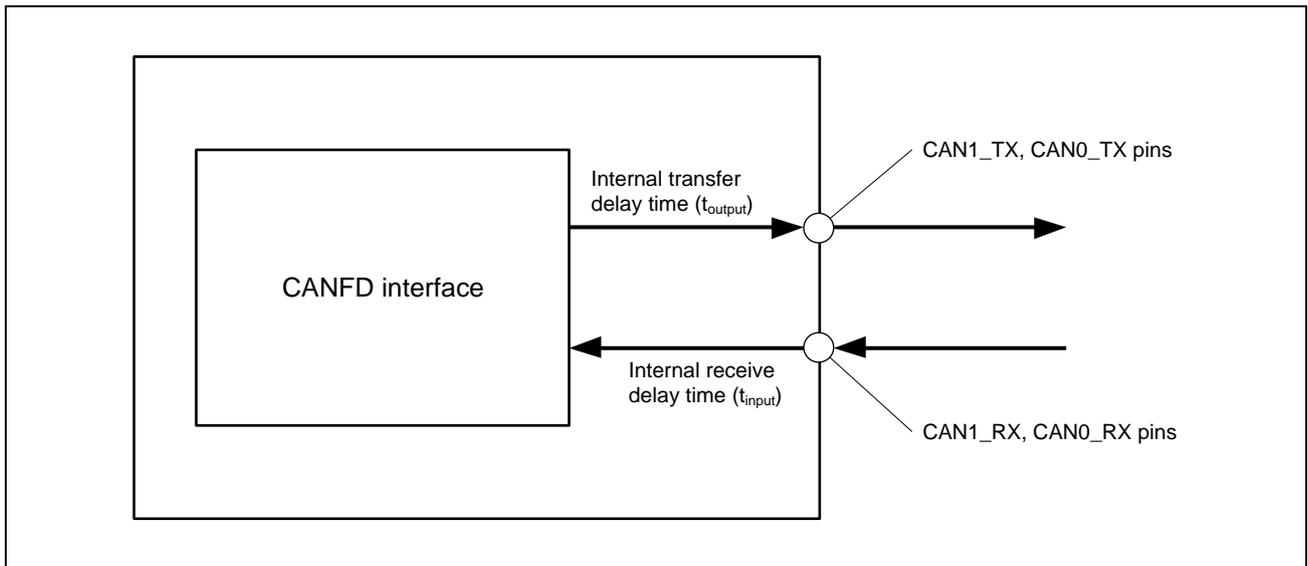
Figure 3.39   CAN-FD Interface Condition

3.5.13   Multi-Function Timer Pulse Unit 3 (MTU3a) Access Timing

Table 3.40   MTU3a Timing

Item			Symbol	Min.	Max.	Unit*1	Figures
MTU3a	Input capture input pulse width	Single-edge setting	t_{MTICW}	1.5	—	t_{p1cyc}*1	**Figure 3.40**
		Both-edge setting		2.5	—		
	Timer clock pulse width	Single-edge setting	t_{MTCKWH}, t_{MTCKWL}	1.5	—	t_{p1cyc}*1	**Figure 3.41**
		Both-edge setting		2.5	—		
		Phase counting mode		2.5	—		

Note: AC access timing condition: drive ability 4mA, output load 30pF, slew rate = fast

Note 1. t_{p1cyc} indicates peripheral clock means MTU_X_MCLK_MTU3 (P0ϕ).
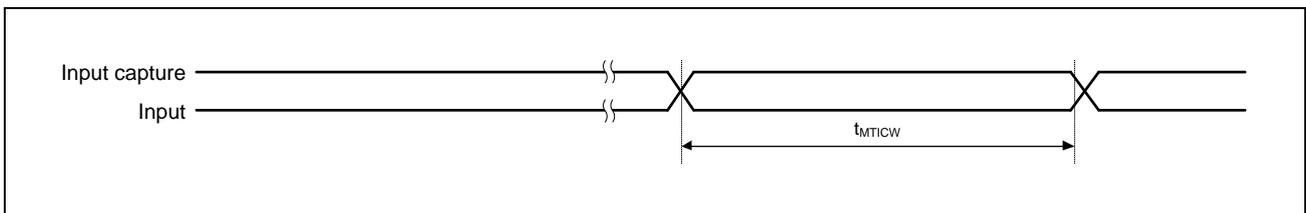
Figure 3.40   MTU3a Input Capture Input Timing
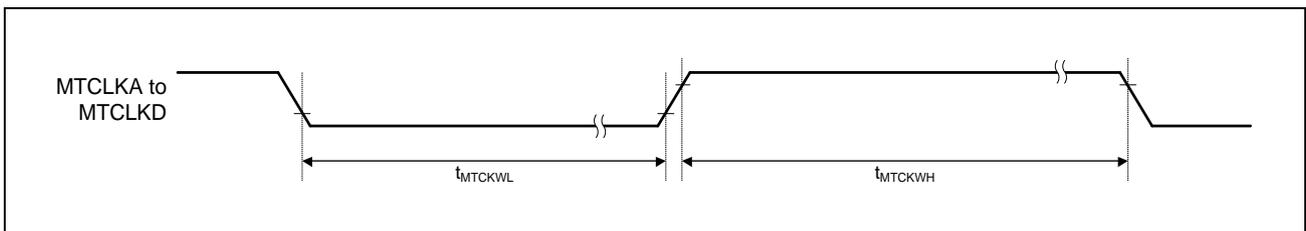
Figure 3.41   MTU3a Clock Input Timing

3.5.14   Port Output Enable 3 (POE3) Access Timing

Table 3.41   POE3 Timing

Item		Symbol	Min.	Max.	Unit	Figures
POE3	POEn# input pulse width	t_{POE3W}	1.5	—	t_{p1cy}[*1]	**Figure 3.42**

Note 1. t_{p1cyc} indicates peripheral clock means POE3_CLKM_POE (P0φ).
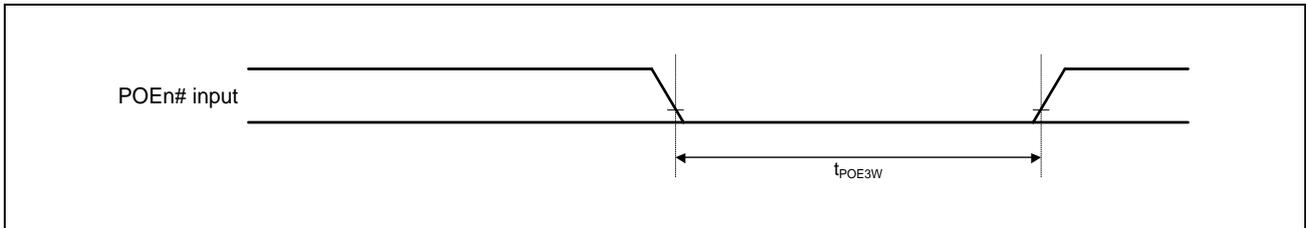
Figure 3.42   POEn# Input Pulse Timing

3.5.15   General PWM Timer (GPT) Access Timing

Table 3.42   GPT Timing

Item			Symbol	Min.	Max.	Unit	Figures
GPT	Input capture input pulse width	Single-edge setting	t_{GTICW}	1.5	—	t_{p1cyc}[*1]	**Figure 3.43**
		Both-edge setting		2.5	—		

Note: AC access timing condition: drive ability 4mA, output load 30pF, slew rate = fast

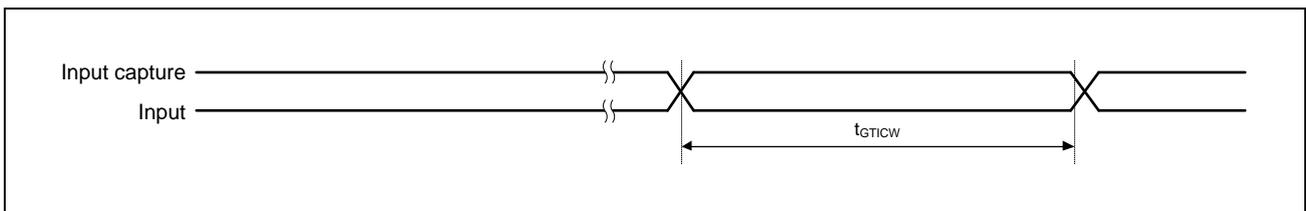Note 1. t_{p1cyc} indicates peripheral clock means GPT_PCLK (P0φ).

Figure 3.43   GPT Input Capture Input Timing

3.5.16   Port Output Enable for GPT (POEG) Access Timing

Table 3.43   POEG Timing

Item		Symbol	Min.	Max.	Unit	Figures
POEG	POEG input pulse width	t_{POEGW}	3	—	t_{p1cyc}[*1]	**Figure 3.44**

Note 1. t_{p1cyc} indicates peripheral clock means POEG_x_CLKP (P0ϕ) (x = A, B, C, D).
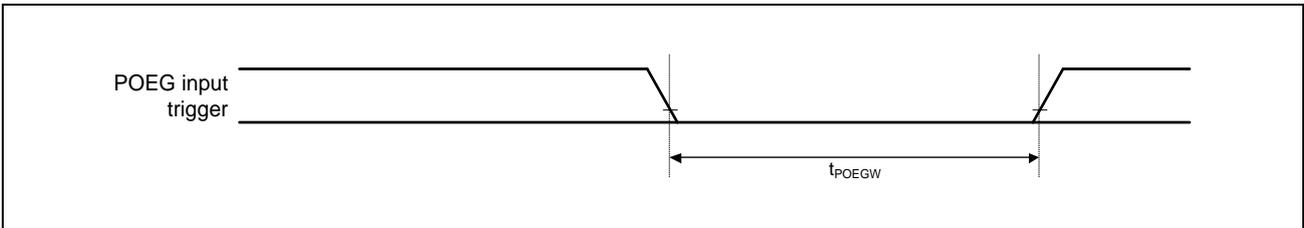
Figure 3.44   POEG Input Trigger Timing

3.5.17   I²C Bus Interface Access Timing

Table 3.44   I²C Bus Interface Timing

Item	Symbol	I/O	Standard Mode (Sm)		Fast Mode (Fm)		Fast Mode Plus (Fm+)		Unit
			Min.	Max.	Min.	Max.	Min.	Max.	
SCL clock frequency	f_{CLK}	I/O	0	100	0	400	0	1000	kHz
Bus free time (between stop and start condition)	t_{BUF}	I/O	4.7	—	1.3	—	0.5	—	µs
Hold time*1	$t_{HD:STA}$	I/O	4.0	—	0.6	—	0.26	—	µs
Low period of SCL clock	t_{LOW}	I/O	4.7	—	1.3	—	0.5	—	µs
High period of SCL clock	t_{HIGH}	I/O	4.0	—	0.6	—	0.26	—	µs
Setup time for start / restart condition	$t_{SU:STA}$	I/O	4.7	—	0.6	—	0.26	—	µs
Data hold time (I²C bus device)	$t_{HD:DAT}$	I/O	0*2	—	0*2	—	0	—	µs
Data setup time	$t_{SU:DAT}$	I/O	250	—	100*3	—	50	—	ns
SDA and SCL signal rise time	t_R	Input	—	1000	20	300	—	120	ns
SDA and SCL signal fall time*3	t_F	Input	—	300	20 × (PV$_{DD}$/ 5.5 V)	300	20 × (PV$_{DD}$/ 5.5 V)	120	ns
		Output	—	300	20 × (PV$_{DD}$/ 5.5 V)*6	300*6	20 × (PV$_{DD}$/ 5.5 V)*7	120*7	ns
Setup time for STOP condition	$t_{SU:STO}$	I/O	4.0	—	0.6	—	0.26	—	µs
Capacitive load for each bus line	C_b	—	—	400*4	—	400*4	—	550*4	pF
Pulse width of spikes that must be suppressed by the input filter	t_{SP}	Input	—	—	0	50*5	0	50*5	ns

Note: In the above table and subsequently, SCL and SDA refer to the RIICnSCL and RIICnSDA signals, respectively.

Note: AC access timing condition: drive ability 4mA, output load 400pF, slew rate = slow

Note 1.   The first clock pulse is generated on the SCL line after the start condition has been issued and the hold time has elapsed.

Note 2.   This module requires a minimum of 300 ns hold time internally for the SDA signal to handle the period over which the falling edge of SCL has not reached a defined level (time until the CnSCL signal reaches V_{IL} (max.) from V_{IH} (min.)).

Note 3.   The fast-mode I²C bus device can be used in the standard mode I²C bus system. In this case, the minimum value of the data setup time ($t_{SU:\ DAT}$ (min.) 250 [ns]) must be satisfied.
If the system does not extend the low period of SCL clock (t_{LOW}), this condition is automatically satisfied. If the system extends the low period of SCL clock (t_{LOW}), transmit the subsequent data bit to the SDA line before the SCL line is released (t_R (max.) + $t_{SU:\ DAT}$ (min.) = 1000 + 250 = 1250 [ns]: (standard mode I²C bus specification)).

Note 4.   Total capacitance of one bus line. The allowable maximum bus capacitance may differ from this specification, depending on the actual operating voltage and frequency of an application. For techniques to cope with a large bus capacitance, see the I²C bus specification provided by NXP Semiconductors.

Note 5.   Noise is removed by the analog and digital input filters. The level of noise reduction of the digital input filter is determined by the period of internal reference clock (IICφ) and the NF[1:0] bits in RIICnMR3. For details, refer to *Section 26, I²C Bus Interface*, in the *User's Manual: Hardware*.

Note 6.   External pull-up resistor is required 1077Ω to 1770Ω when using RIIC ch2 or RIIC ch3.

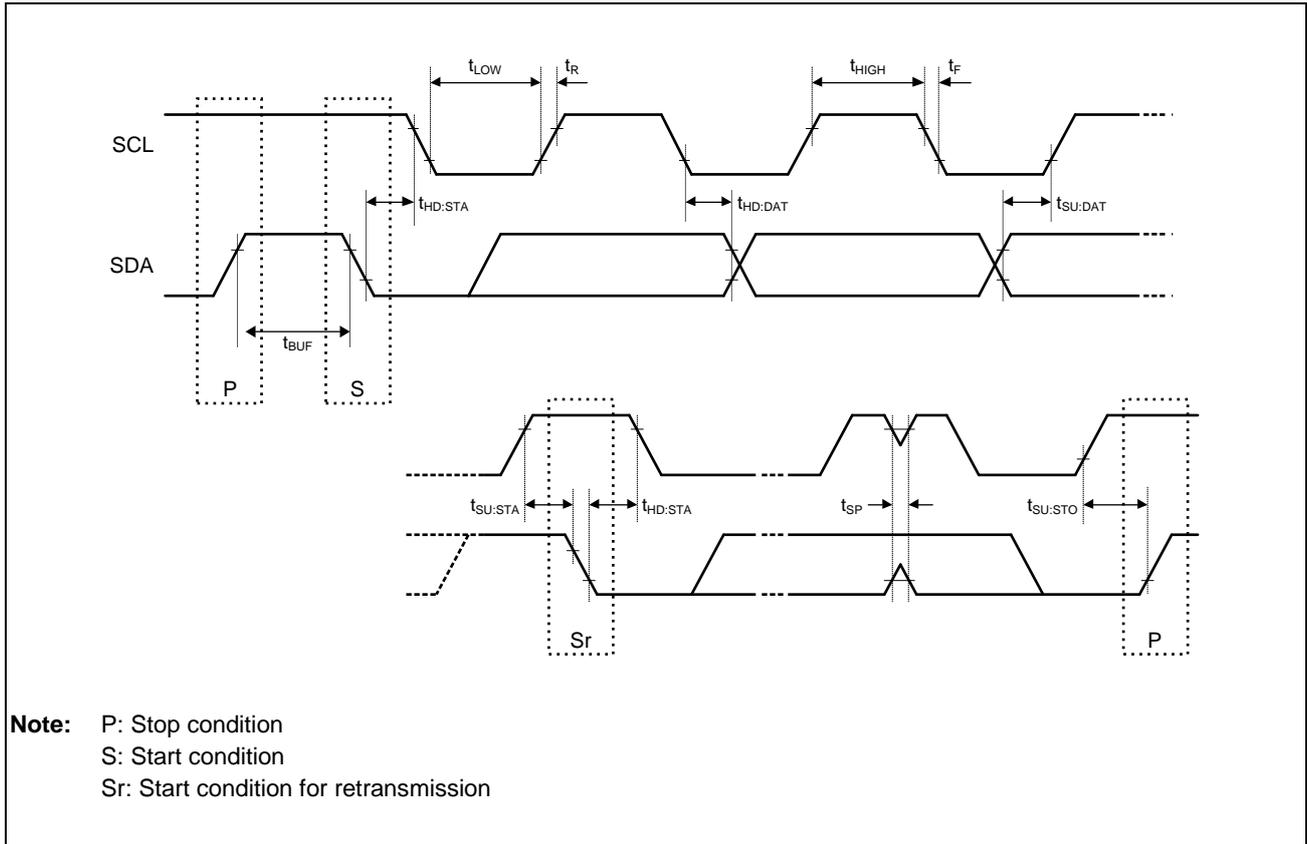Note 7.   External pull-up resistor is required 240Ω to 257Ω when using RIIC ch2 or RIIC ch3.

Note: P: Stop condition
         S: Start condition
         Sr: Start condition for retransmission

Figure 3.45   Input/Output Timing

3.5.18   Serial Communications Interface with FIFO (SCIFA) Access Timing

Table 3.45   SCIFA Timing

Item			Symbol	Min.	Max.	Unit	Figures
SCIFA	Input clock cycle	Asynchronous	t_{Scyc}	4	—	t_{p1cyc}[1]	**Figure 3.46**
		Clocked synchronous		12	—		
	Input clock pulse width		t_{SCKW}	0.4	0.6	t_{p1cyc}[1]	
	Input clock rise time		t_{SCKr}	—	5	ns	
	Input clock fall time		t_{SCKf}	—	5	ns	
	Output clock cycle	Asynchronous[2]	t_{Scyc}	8	—	t_{p1cyc}[1]	
		Clocked synchronous		4	—		
	Output clock pulse width		t_{SCKW}	0.4	0.6	t_{p1cyc}[1]	
	Output clock rise time		t_{SCKr}	—	9	ns	
	Output clock fall time		t_{SCKf}	—	9	ns	
	Transmit data delay time	Internal clock	t_{TXD}	−10	10	ns	**Figure 3.47**
		External clock		$3 \times t_{p1cyc}$[1]	$4 \times t_{p1cyc}$[1] + 20		
	Receive data setup time	Internal clock	t_{RXS}	$3 \times t_{p1cyc}$[1] + 20	—	ns	
		External clock		t_{p1cyc}[1] + 10	—		
	Receive data hold time	Internal clock	t_{RXH}	$-3 \times t_{p1cyc}$[1]	—	ns	
		External clock		$2 \times t_{p1cyc}$[1] + 10	—		

Note: AC access timing condition: drive ability 12mA, output load 30pF, slew rate = fast

Note 1. t_{p1cyc} indicates peripheral clock means SCIFn_CLK_PCK (P0ϕ) (n = 0 to 4).

Note 2.   When the SEMR.ABCS0 and SEMR.BGDM bits are set to 1.
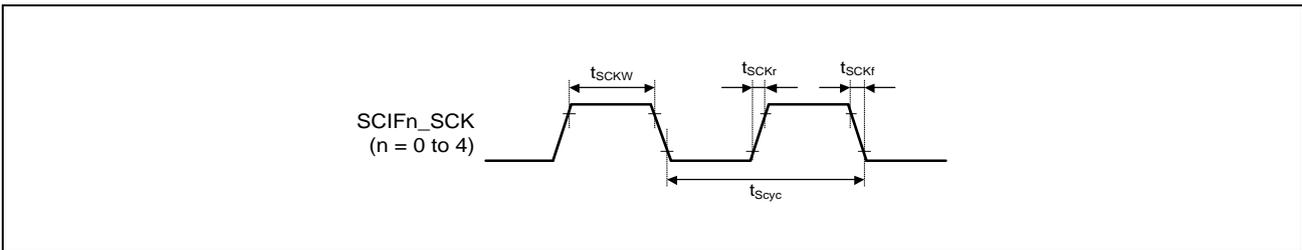

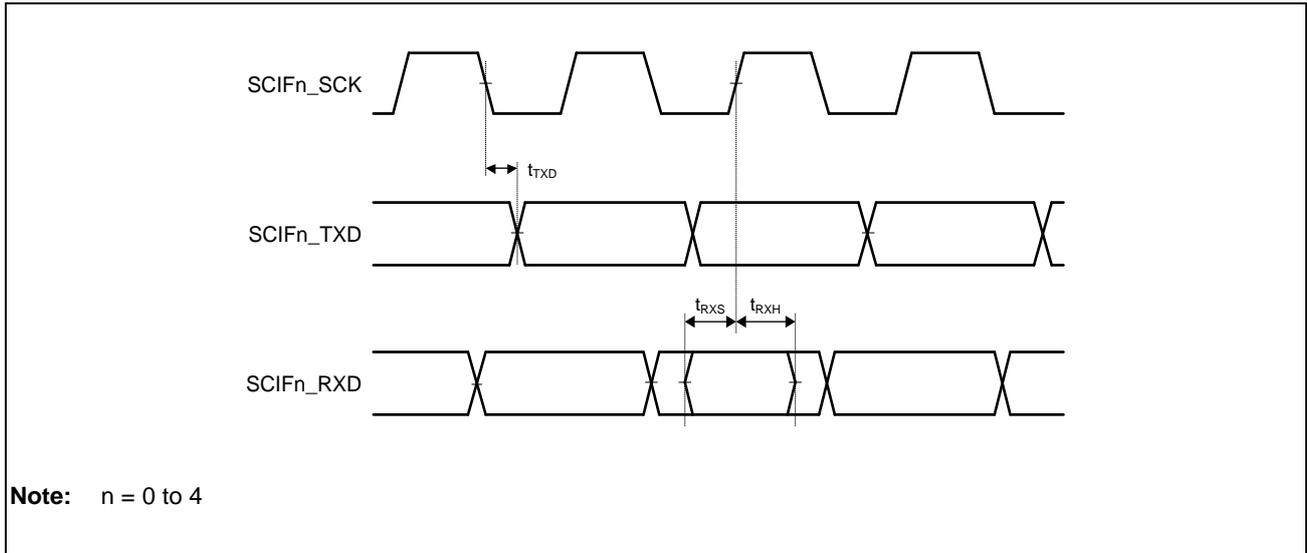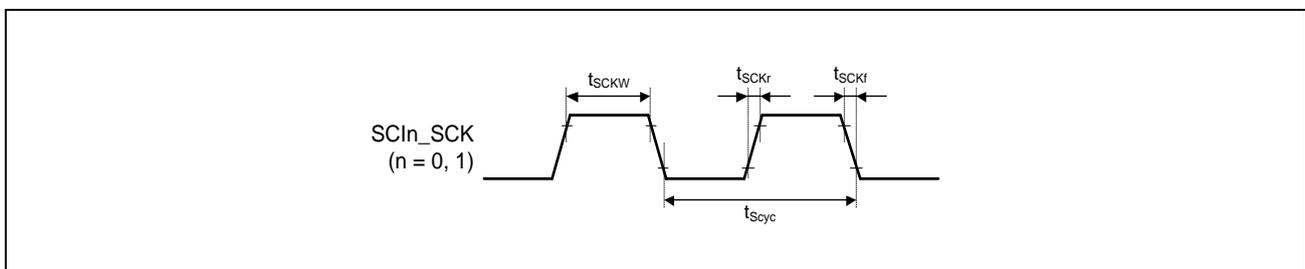Figure 3.46   SCK Input Clock Timing

Figure 3.47   SCIFA Input/Output Timing in Clocked Synchronous Mode

3.5.19 Serial Communications Interface (SCIg) Access Timing

Table 3.46   SCIg Timing

Item			Symbol	Min.	Max.	Unit	Figures
SCIg	Input clock cycle	Asynchronous	t_{Scyc}	4	—	t_{p1cyc}[*1]	**Figure 3.48**
		Clocked synchronous		6	—		
	Input clock pulse width		t_{SCKW}	0.4	0.6	t_{p1cyc}[*1]	
	Input clock rise time		t_{SCKr}	—	5	ns	
	Input clock fall time		t_{SCKf}	—	5	ns	
	Output clock cycle	Asynchronous[*2]	t_{Scyc}	8	—	t_{p1cyc}[*1]	
		Clocked synchronous		4	—		
	Output clock pulse width		t_{SCKW}	0.4	0.6	t_{p1cyc}[*1]	
	Output clock rise time		t_{SCKr}	—	5	ns	
	Output clock fall time		t_{SCKf}	—	5	ns	
	Transmit data delay time	Clocked synchronous	t_{TXD}	—	28	ns	**Figure 3.49**
	Receive data setup time	Clocked synchronous	t_{RXS}	15	—	ns	
	Receive data hold time	Clocked synchronous	t_{RXH}	5	—	ns	

Note: AC access timing condition: drive ability 12mA, output load 30pF, slew rate = fast

Note 1. t_{p1cyc} indicates peripheral clock means SCIn_CLKP (P0ϕ) (n = 0 to 1).

Note 2.   When the SEMR.ABCS0 and SEMR.BGDM bits are set to 1.

Figure 3.48   SCK Input Clock Timing
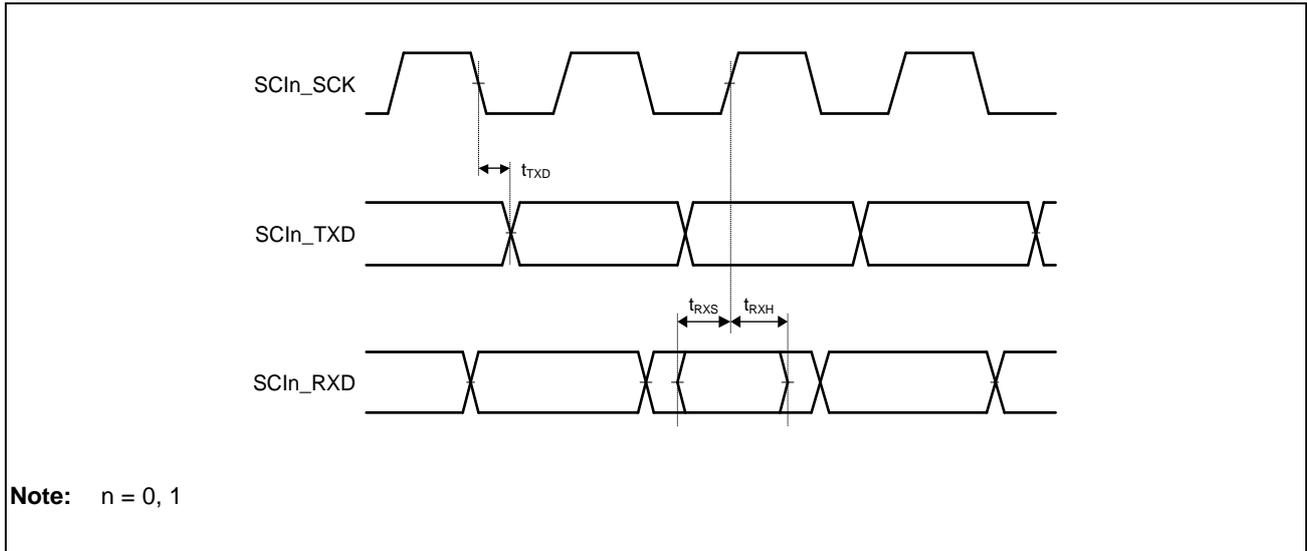
Note: n = 0, 1

Figure 3.49   SCIFA Input/Output Timing in Clocked Synchronous Mode

3.5.20 Renesas Serial Peripheral Interface (RSPI) Access Timing

Table 3.47 Renesas Serial Peripheral Interface Timing

Item		Symbol	Min.	Max.	Unit	Figure
RSPCK clock cycle	Master	t_{SPcyc}	2	4096	t_{p1cyc}[*1]	**Figure 3.50**
	Slave		8	4096		
RSPCK clock high pulse width	Master	t_{SPCKWH}	0.4	—	t_{SPcyc}[*1]	
	Slave		0.4	—		
RSPCK clock low pulse width	Master	t_{SPCKWL}	0.4	—	t_{SPcyc}[*1]	
	Slave		0.4	—		
Data input setup time	Master	t_{SU}	10	—	ns	**Figure 3.51** to **Figure 3.54**
	Slave		0	—	t_{p1cyc}[*1]	
Data input hold time	Master	t_{H}	0	—	ns	
	Slave		4	—	t_{p1cyc}[*1]	
SSL setup time	Master	t_{LEAD}	$1 \times t_{SPcyc} - 20$	$8 \times t_{SPcyc}$	ns	
	Slave		4	—	t_{p1cyc}[*1]	
SSL hold time	Master	t_{LAG}	$1 \times t_{SPcyc}$	$8 \times t_{SPcyc} + 20$	ns	
	Slave		4	—	t_{p1cyc}[*1]	
Data output delay time	Master	t_{OD}	—	19	ns	
	Slave		—	4	t_{p1cyc}[*1]	
Data output hold time	Master	t_{OH}	5	—	ns	
	Slave		2	—	t_{p1cyc}[*1]	
Continuous transmission delay time	Master	t_{TD}	$1 \times t_{SPcyc} + 2 \times t_{cyc}$	$8 \times t_{SPcyc} + 2 \times t_{cyc}$	ns	
	Slave		$4 \times t_{cyc}$	—		
Slave access time		t_{SA}	—	4	t_{p1cyc}[*1]	**Figure 3.53**, **Figure 3.54**
Slave out release time		t_{REL}	—	3	t_{p1cyc}[*1]	

Note: AC access timing condition: drive ability 12mA, output load 30pF, slew rate = fast

Note 1. t_{p1cyc} indicates peripheral clock means RSPIn_CLKB (P0ϕ) (0 to 2).
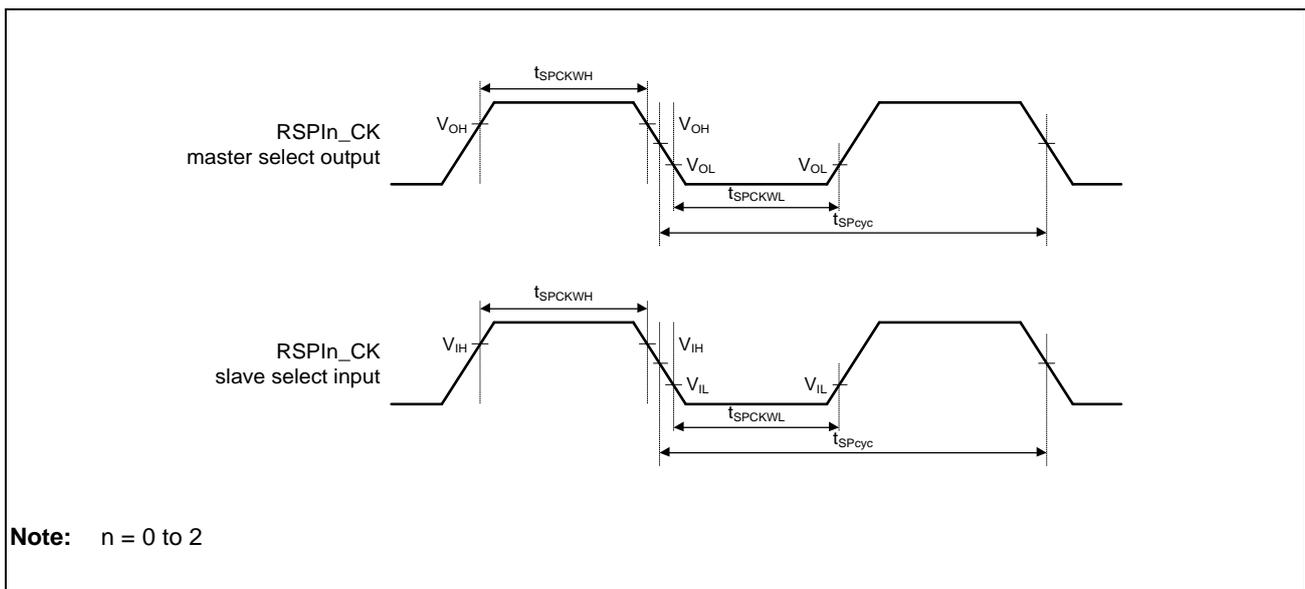

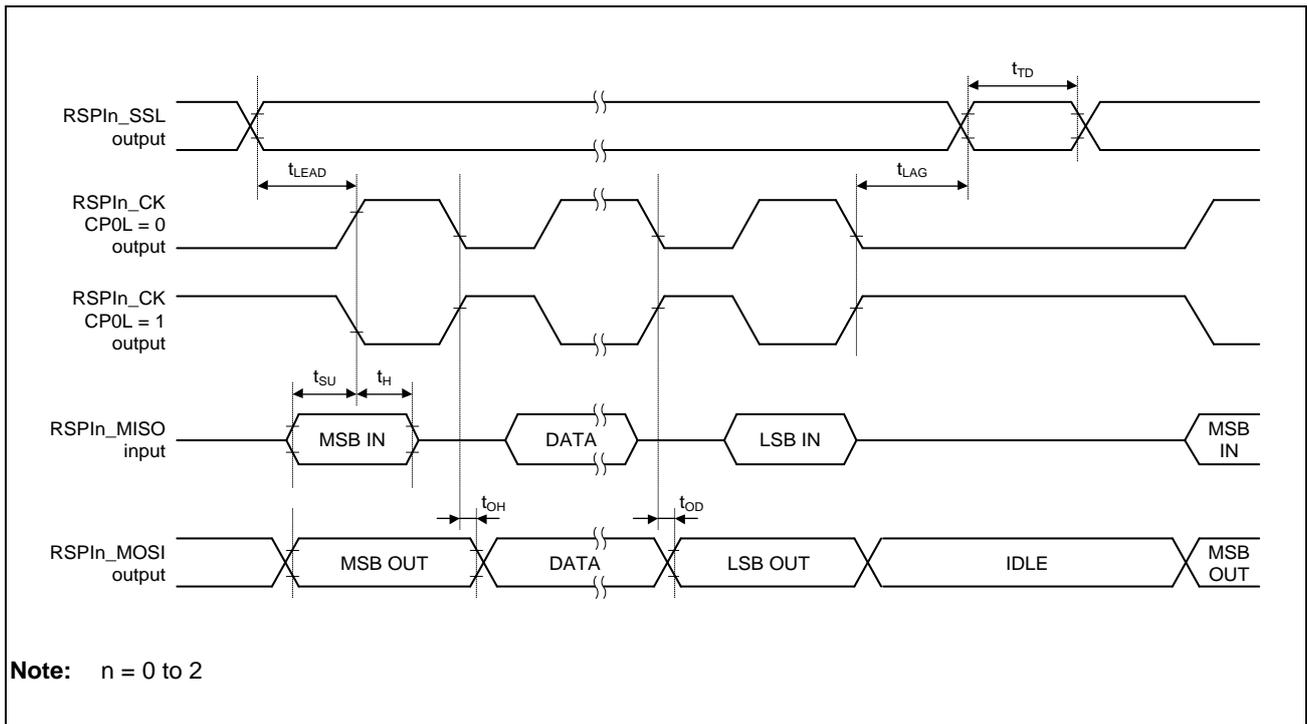
Figure 3.50 Clock Timing

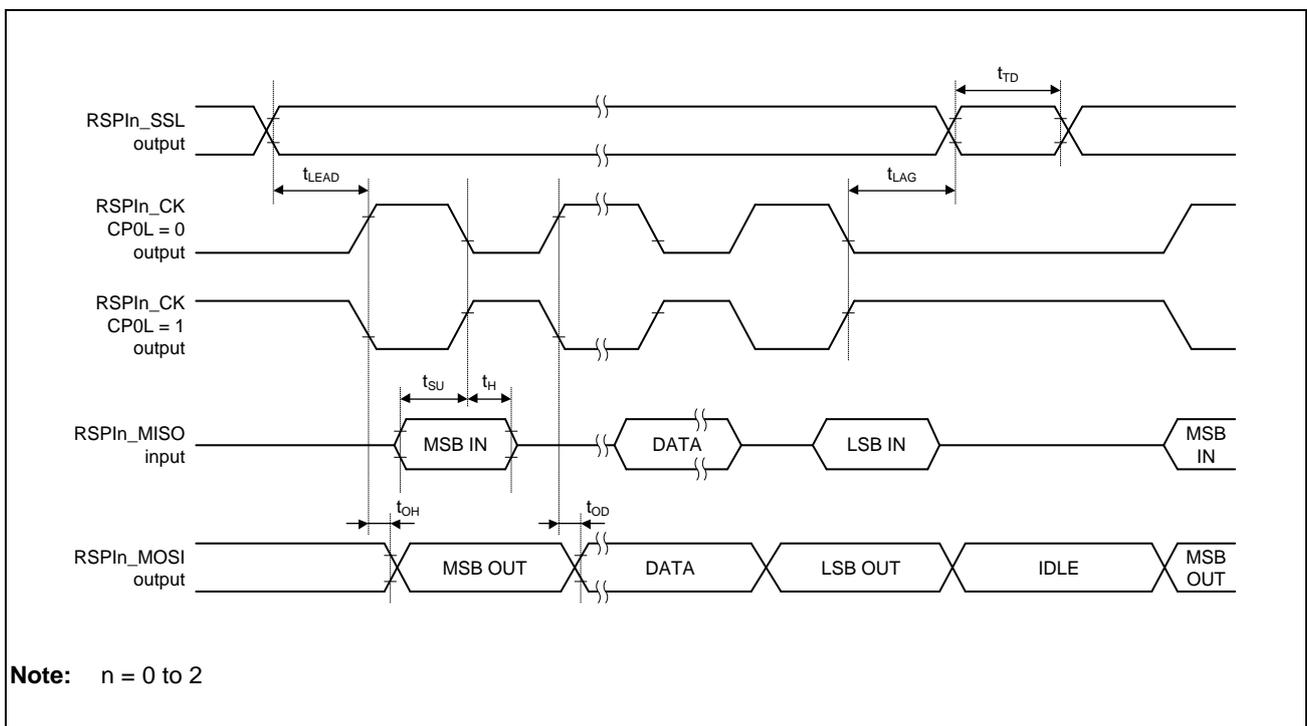Figure 3.51   Transmission and Reception Timing (Master, CPHA = 0)

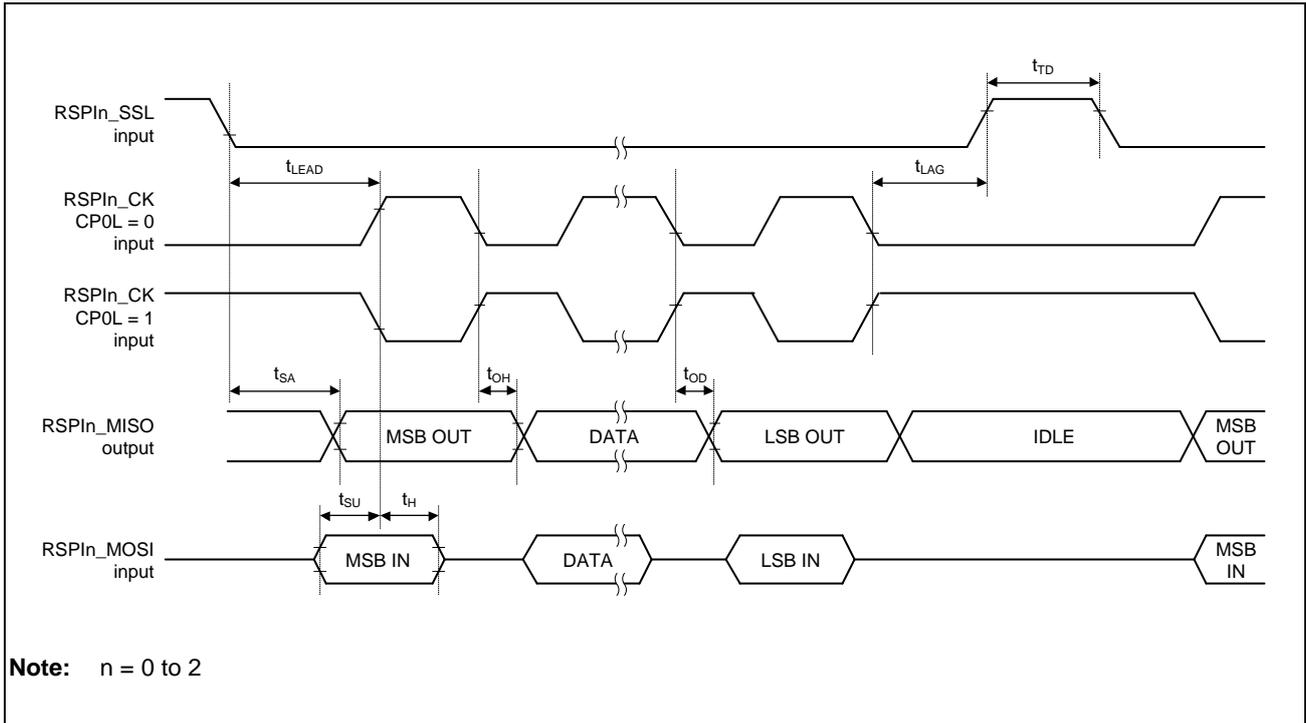Figure 3.52   Transmission and Reception Timing (Master, CPHA = 1)

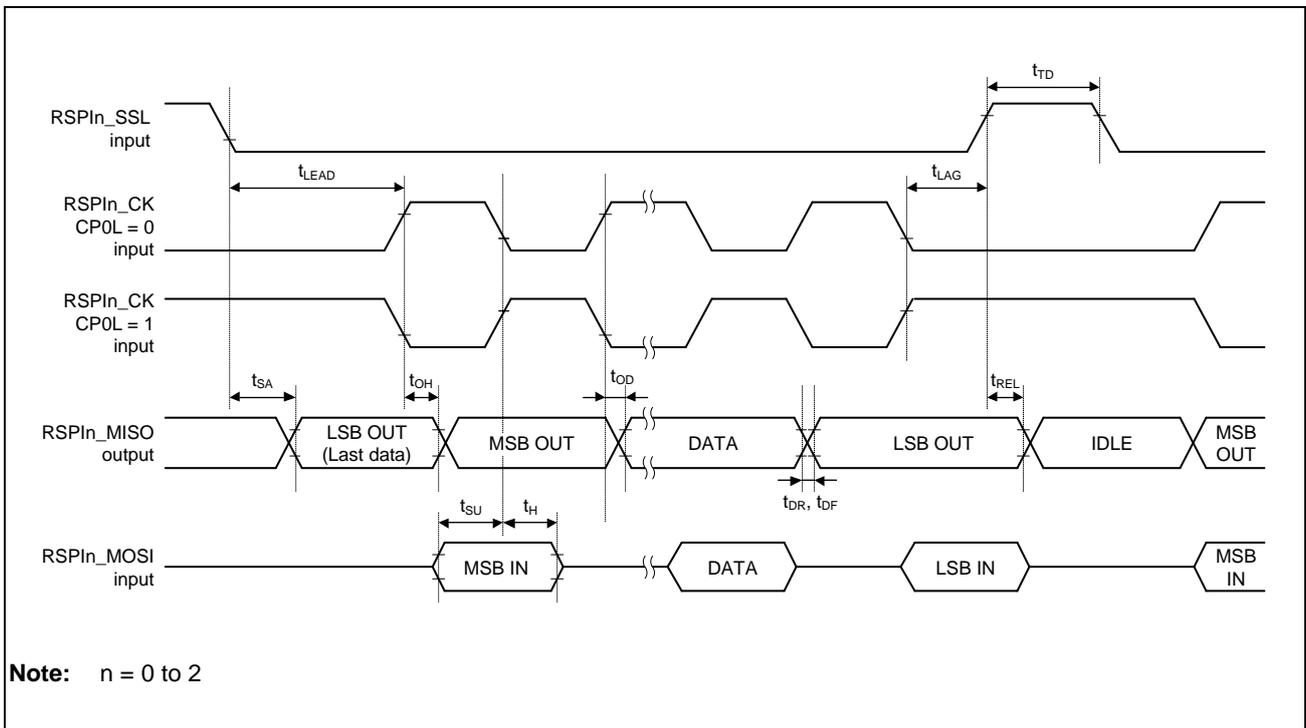Figure 3.53   Transmission and Reception Timing (Slave, CPHA = 0)

Figure 3.54   Transmission and Reception Timing (Slave, CPHA = 1)

3.5.21   A/D Converter Access Timing

Table 3.48   A/D Converter Timing

Item	Symbol	Min.	Max.	Unit	Figures
ADC Trigger Input Pulse Width	t_{TRGW}	1.5[2]		t_{P1cyc}[1]	**Figure 3.55**

Note 1. t_{p1cyc} indicates peripheral clock means ADC_ADCLK (TSUφ).

Note 2.   When a noise filter in ADC is off.
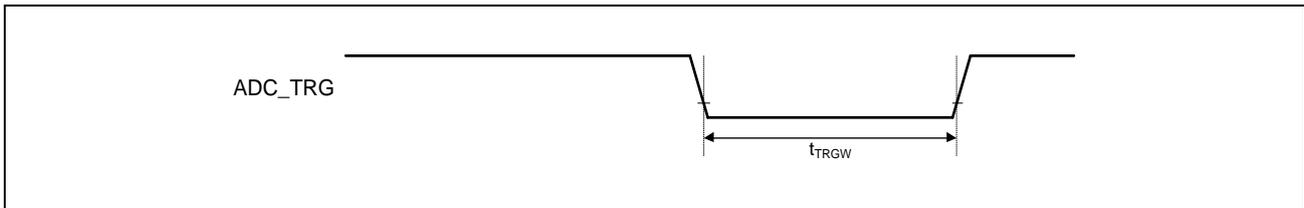

Figure 3.55   ADC Trigger Input Timing

3.5.22   Watchdog Timer Access Timing

Table 3.49   Watchdog Timer Timing

Item	Symbol	Min.	Max.	Unit	Figures
WDTOVF_PERROUT# Output Time	t_L	64	64	t_{P1cyc}[1]	**Figure 3.56**

Note 1. t_{P1cyc} indicates peripheral clock means WDTn_CLK (OSCCLK) (n = 0 to 2).
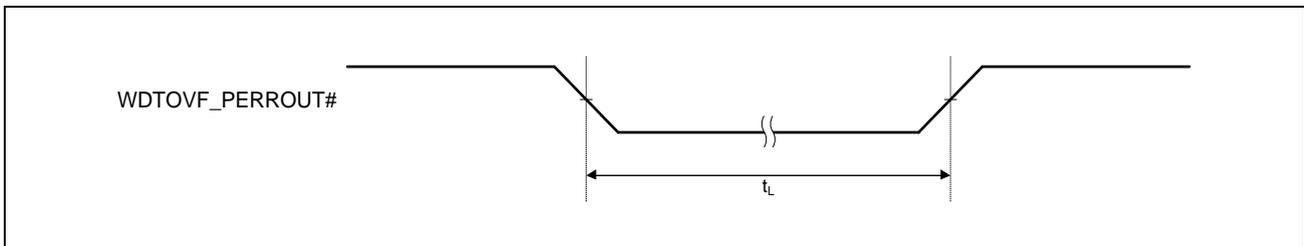
Figure 3.56   Watchdog Timer Output Timing

4.   Package Dimensions

JEITA Package code	RENESAS code	MASS(TYP.)[g]
P-LFBGA551-21x21-0.80	PLBG0551GA-A	1.02
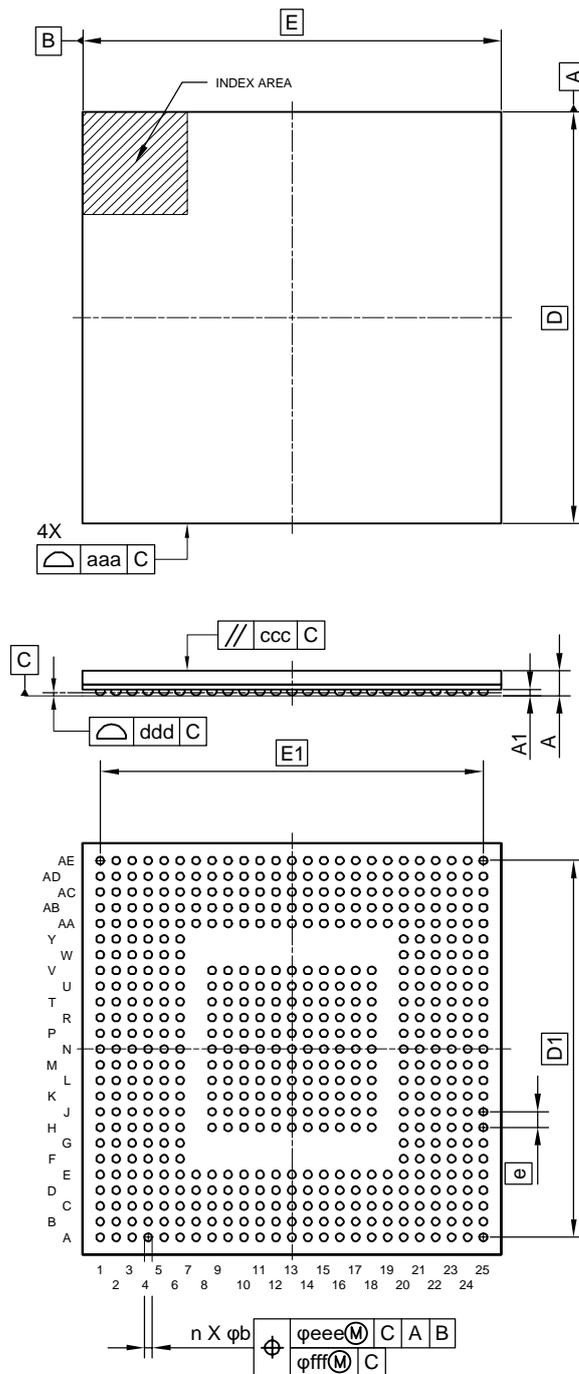
Reference Symbol	Dimension in Millimeters		
	Min.	Nom.	Max.
D	—	21.00	—
E	—	21.00	—
D1	—	19.20	—
E1	—	19.20	—
A	—	—	1.40
A1	0.27	—	—
b	0.38	0.43	0.48
e	—	0.80	—
aaa	—	—	0.15
ccc	—	—	0.35
ddd	—	—	0.20
eee	—	—	0.15
fff	—	—	0.08
n	—	551	—

Figure 4.1   Package Dimensions for LFBGA 21 mm□/0.8 mm pitch/551 pin

JEITA Package code	RENESAS code	MASS(TYP.)[g]
P-LFBGA456-15x15-0.50	PLBG0456KB-A	0.53
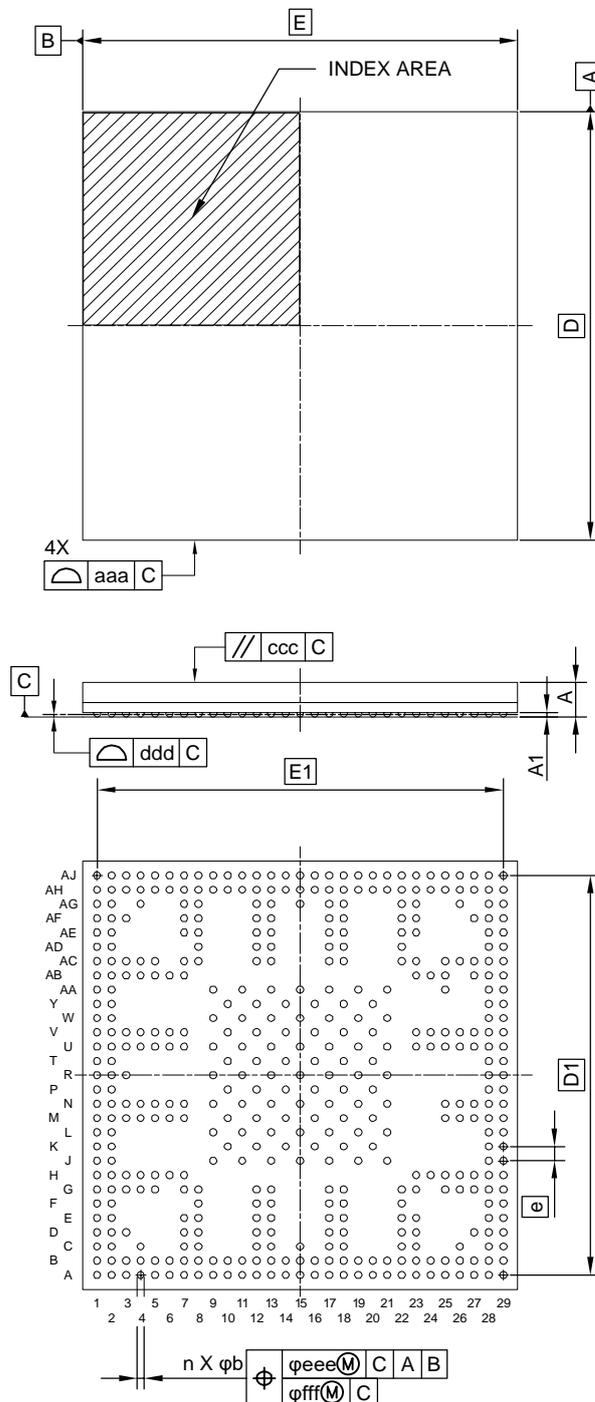
Reference Symbol	Dimension in Millimeters		
	Min.	Nom.	Max.
D	—	15.00	—
E	—	15.00	—
D1	—	14.00	—
E1	—	14.00	—
A	—	—	1.40
A1	0.11	—	—
b	0.20	0.25	0.30
e	—	0.50	—
aaa	—	—	0.15
ccc	—	—	0.20
ddd	—	—	0.08
eee	—	—	0.15
fff	—	—	0.08
n	—	456	—

Figure 4.2   Package Dimensions for LFBGA 15 mm□/0.5 mm pitch/456 pin

REVISION HISTORY	RZ/V2L Group DATASHEET

Rev.	Date	Description	
		Page	Summary
1.00	Dec 25, 2024	—	First edition issued
1.10	May 30, 2025	1. Overview	
		4	1.1.4 External Memory Interface SPI Multi I/O Bus Controller: The description, modified (Note, added)
		13	Figure 1.1 Configuration of LSI Internal Bus Text, modified (MPU Bus → MCPU Bus) SRC, deleted
		14	Table 1.1 Product Lineup Note 2, added
		3. Electrical Characteristics	
		20	Table 3.3 DC Characteristics (1) [3.3-V I/O] Input leakage current, added
		21	Table 3.7 DC Characteristics (5) [RGMII/MII] Input logic low (Remarks: 1.8-V RGMII/MII): The Min value, modified
		22	Table 3.9 DC Characteristics (7) [1.8 V I/O (SD, QSPI)] Output logic high voltage: The Min value, modified Output logic low voltage: The Max value, modified
		24	Table 3.18 DC Characteristics (16) [ADC] Full-scale error, Offset error, Analog input capacitance, Analog input resistance, External capacitance, and External resistance, added Note 1, added
		25	Figure 3.4 Analog Input Equivalent Circuit, added
		29	Table 3.21 SDHC AC Access Timing (SDR at 3.3-V Operation) SD_CLK clock high level width, SD_CLK clock low level width, SD_CMD,SD_DATA output delay: The Min values, modified
		30	Table 3.22 eMMC Host Interface Timing (MMC Default 3.3-V Power Supply) SD0_CLK clock cycle, SD0_CLK clock high level width, SD0_CLK clock low level width, SD0_CMD/SDDAT output delay: The Min values, modified
		30	Table 3.23 eMMC Host Interface Timing (MMC Default 1.8-V Power Supply) SD0_CLK clock cycle, SD0_CLK clock high level width, SD0_CLK clock low level width: The Min values, modified SD0_CMD/SDDAT output delay: The Min and Max values, modified
		31	3.5.3.2 eMMC host interface timing (HS-SDR), modified
		32	Table 3.26 eMMC Host Interface Timing (HS200 1.8-V Power Supply Operation, Output Load 15 pF) SD0_CLK clock high level width, SD0_CLK clock low level width: The Min values, modified SD0_CMD/SDDAT output delay: The Min and Max values, modified
		40	Table 3.34 Ethernet-IF Access Timing (Ether RGMII) Duty cycle for gigabit: The Min and Max values, modified Note, modified

General Precautions in the Handling of Microprocessing Unit and Microcontroller Unit Products

The following usage notes are applicable to all Microprocessing unit and Microcontroller unit products from Renesas. For detailed usage notes on the products covered by this document, refer to the relevant sections of the document as well as any technical updates that have been issued for the products.

1. Precaution against Electrostatic Discharge (ESD)

    A strong electrical field, when exposed to a CMOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop the generation of static electricity as much as possible, and quickly dissipate it when it occurs. Environmental control must be adequate. When it is dry, a humidifier should be used. This is recommended to avoid using insulators that can easily build up static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work benches and floors must be grounded. The operator must also be grounded using a wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions must be taken for printed circuit boards with mounted semiconductor devices.

2. Processing at power-on

    The state of the product is undefined at the time when power is supplied. The states of internal circuits in the LSI are indeterminate and the states of register settings and pins are undefined at the time when power is supplied. In a finished product where the reset signal is applied to the external reset pin, the states of pins are not guaranteed from the time when power is supplied until the reset process is completed. In a similar way, the states of pins in a product that is reset by an on-chip power-on reset function are not guaranteed from the time when power is supplied until the power reaches the level at which resetting is specified.

3. Input of signal during power-off state

    Do not input signals or an I/O pull-up power supply while the device is powered off. The current injection that results from input of such a signal or I/O pull-up power supply may cause malfunction and the abnormal current that passes in the device at this time may cause degradation of internal elements. Follow the guideline for input signal during power-off state as described in your product documentation.

4. Handling of unused pins

    Handle unused pins in accordance with the directions given under handling of unused pins in the manual. The input pins of CMOS products are generally in the high-impedance state. In operation with an unused pin in the open-circuit state, extra electromagnetic noise is induced in the vicinity of the LSI, an associated shoot-through current flows internally, and malfunctions occur due to the false recognition of the pin state as an input signal become possible.

5. Clock signals

    After applying a reset, only release the reset line after the operating clock signal becomes stable. When switching the clock signal during program execution, wait until the target clock signal is stabilized. When the clock signal is generated with an external resonator or from an external oscillator during a reset, ensure that the reset line is only released after full stabilization of the clock signal. Additionally, when switching to a clock signal produced with an external resonator or by an external oscillator while program execution is in progress, wait until the target clock signal is stable.

6. Voltage application waveform at input pin

    Waveform distortion due to input noise or a reflected wave may cause malfunction. If the input of the CMOS device stays in the area between V_{IL} (Max.) and V_{IH} (Min.) due to noise, for example, the device may malfunction. Take care to prevent chattering noise from entering the device when the input level is fixed, and also in the transition period when the input level passes through the area between V_{IL} (Max.) and V_{IH} (Min.).

7. Prohibition of access to reserved addresses

    Access to reserved addresses is prohibited. The reserved addresses are provided for possible future expansion of functions. Do not access these addresses as the correct operation of the LSI is not guaranteed.

8. Differences between products

    Before changing from one product to another, for example to a product with a different part number, confirm that the change will not lead to problems. The characteristics of a microprocessing unit or microcontroller unit products in the same group but having a different part number might differ in terms of internal memory capacity, layout pattern, and other factors, which can affect the ranges of electrical characteristics, such as characteristic values, operating margins, immunity to noise, and amount of radiated noise. When changing to a product with a different part number, implement a system-evaluation test for the given product.

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